## MEMORY cmos

## 8 x 256K x 32 BIT, FCRAM™ CORE BASED DOUBLE DATA RATE SDRAM

# MB81P643287-50/-60

#### CMOS 8-BANK x 262,144-WORD x 32 BIT, FCRAM Core Based Synchronous Dynamic Random Access Memory with Double Data Rate

### DESCRIPTION

The Fujitsu MB81P643287 is a CMOS Synchronous Dynamic Random Access Memory (SDRAM) with Fujitsu advanced FCRAM (Fast Cycle Random Access Memory) Core Technology, containing 67,108,864 memory cells accessible in an 32-bit format. The MB81P643287 features a fully synchronous operation referenced to clock edge whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence. The MB81P643287 is designed to reduce the complexity of using a standard dynamic RAM (DRAM) which requires many control signal timin.g constraints. The MB81P643287 uses Double Data Rate (DDR) where data bandwidth is twice of fast speed compared with regular SDRAMs.

The MB81P643287 is ideally suited for Digital Visual Systems, High Performance Graphic Adapters, Hardware Accelerators, Buffers, and other applications where large memory density and high effective bandwidth are required and where a simple interface is needed.

The MB81P643287 adopts new I/O interface circuitry, SSTL\_2 interface, which is capable of extremely fast data transfer of quality under either terminated or point to point bus environment.

## PRODUCT LINE

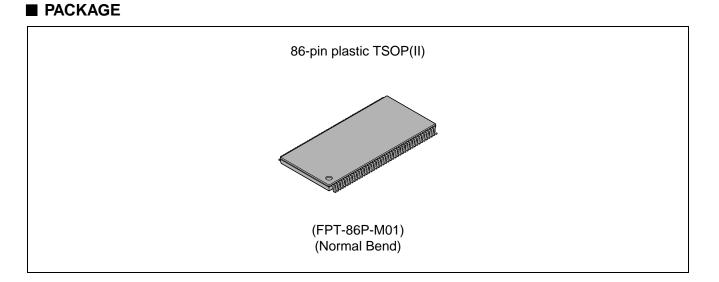
Parameter		MB81P643287				
Farameter		-50	-60			
Clock Frequency	CL = 3	200 MHz Max.	167 MHz Max.			
Clock Frequency	CL = 2	133 MHz Max.	111 MHz Max.			
Rurat Mada Civala Tima	CL = 3	2.5 ns Min.	3.0 ns Min.			
Burst Mode Cycle Time	CL = 2	3.75 ns Min.	4.5 ns Min.			
Random Address Cycle Time		30 ns Min.	36 ns Min.			
DQS Access Time From Clock		0.1 × tск + 0.2 ns Max.	0.1 × tск + 0.2 ns Max.			
Operating Current		460 mA Max. 405 mA Max.				
Power Down Current		35 mA Max.				

Note: FCRAM is a trademark of Fujitsu Limited, Japan.

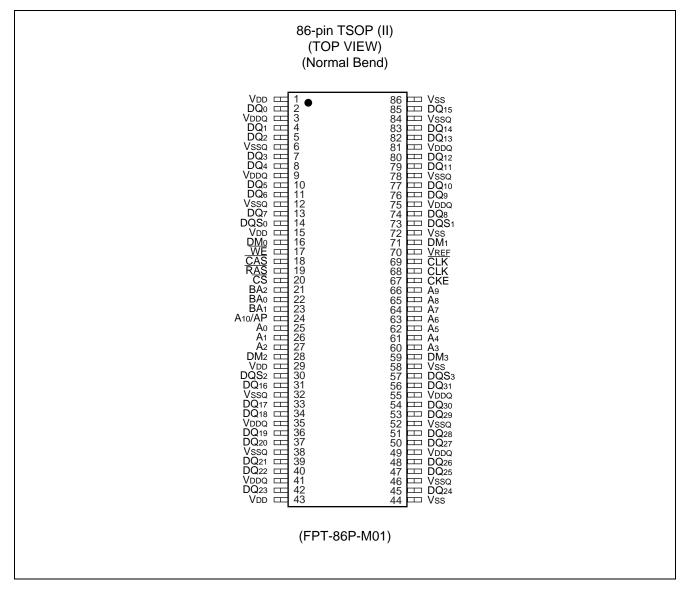
## ■ FEATURES

- Double Data Rate
- Bi-directional Data Strobe Signal
- Eight bank operation
- Burst read/write operation
- Programmable burst length and CAS latency
- Byte write control by DMo to DM3
- Standby Power Down Mode

- 4096 Auto-refresh cycles in 32 ms
- SSTL\_2 (class 2) for all signals
- V<sub>DD</sub>: +2.5V Supply ± 0.2V tolerance
- VDDQ: +2.5V Supply ± 0.2V tolerance



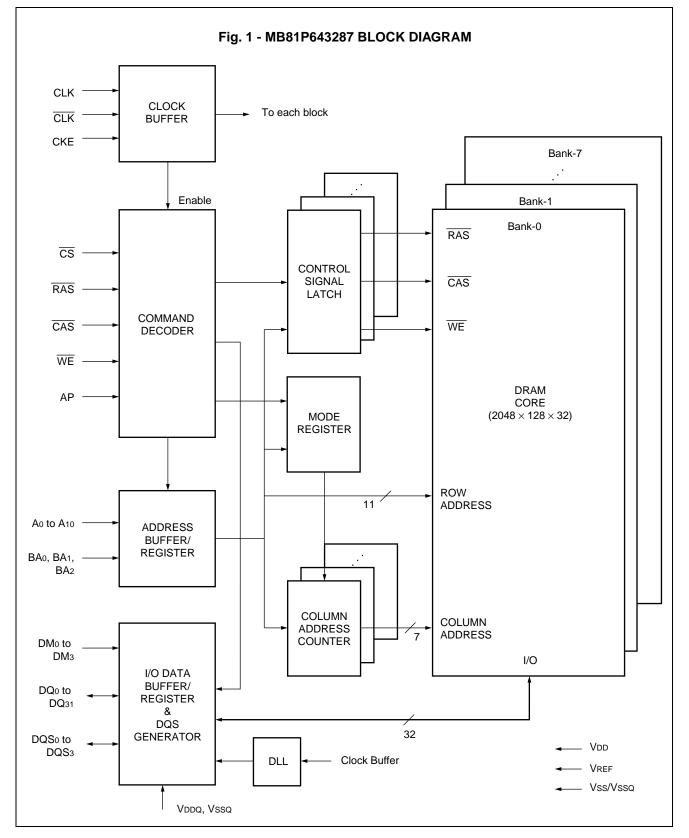




## ■ DESCRIPTIONS

Pin Number	Symbol	Function
1, 3, 9, 15, 29, 35, 41, 43, 49, 55, 75, 81	Vdd, Vddq	Supply Voltage
6, 12, 32, 38, 44, 46, 52, 58, 72, 78, 84, 86	Vss, Vssq	Ground
2, 4, 5, 7, 8, 10, 11, 13, 31, 33, 34, 36, 37, 39, 40, 42, 45, 47, 48, 50, 51, 53, 54, 56, 74, 76, 77, 79, 80, 82, 83, 85	DQ <sub>0</sub> to DQ <sub>31</sub>	<ul> <li>Byte 0: DQ<sub>0</sub> to DQ<sub>7</sub></li> <li>Byte 1: DQ<sub>8</sub> to DQ<sub>15</sub></li> <li>Byte 2: DQ<sub>16</sub> to DQ<sub>23</sub></li> <li>Byte 3: DQ<sub>24</sub> to DQ<sub>31</sub></li> </ul>
14, 30, 57, 73	DQS₀ to DQS₃	Data Strobe• DQS0: for DQ0 to DQ7• DQS1: for DQ8 to DQ15• DQS2: for DQ16 to DQ23• DQS3: for DQ24 to DQ31
16, 28, 59, 71	DM <sub>0</sub> to DM <sub>3</sub>	Input Mask
17	WE	Write Enable
18	CAS	Column Address Strobe
19	RAS	Row Address Strobe
20	CS	Chip Select
21, 22, 23	BA2, BA1, BA0	Bank Select (Bank Address)
24	AP	Auto Precharge Enable
24, 25, 26, 27, 60, 61, 62, 63, 64, 65, 66	A <sub>0</sub> to A <sub>10</sub>	Address Input <ul> <li>Row: A<sub>0</sub> to A<sub>10</sub></li> <li>Column: A<sub>0</sub> to A<sub>6</sub></li> </ul>
67	CKE	Power Down
68	CLK	Clock Input
69	CLK	Clock Input
70	Vref	Input Reference Voltage

## BLOCK DIAGRAM



## ■ FUNCTION TRUTH TABLE (Note\*1)

#### COMMAND TRUTH TABLE (Note \*2, and \*3)

Function	Notes	Symbol	CKE	CS	RAS	CAS	WE	<b>BA</b> 2-0	<b>A</b> 10/ <b>AP</b>	<b>A</b> 9-7	<b>A</b> 6-0
Device Deselect	*4	DESL	Н	Н	Х	Х	Х	Х	Х	Х	Х
No Operation	*4	NOP	Н	L	Н	Н	Н	Х	Х	Х	Х
Burst Stop	*5	BST	Н	L	Н	Н	L	Х	Х	Х	Х
Read	*6	READ	Н	L	Н	L	Н	V	L	Х	V
Read with Auto-precharge	*6	READA	Н	L	Н	L	Н	V	Н	Х	V
Write	*6	WRIT	Н	L	Н	L	L	V	L	Х	V
Write with Auto-precharge	*6	WRITA	Н	L	Н	L	L	V	Н	Х	V
Bank Active (RAS)	*7	ACTV	Н	L	L	Н	Н	V	V	V	V
Precharge Single Bank	*8	PRE	Н	L	L	Н	L	V	L	Х	Х
Precharge All Banks	*8	PALL	Н	L	L	Н	L	V	Н	Х	Х
Mode Register Set/ Extended Mode Register Set	*8,9,10	MRS/ EMRS	Н	L	L	L	L	V	L	V	V

Notes: \*1. V = Valid, L = Logic Low, H = Logic High, X = either L or H, Hi-Z = High Impedance.

\*2. All commands are assumed to be valid state transitions.

\*3. All inputs for command are latched on the rising edge of clock(CLK).

\*4. NOP and DESL commands have the same effect on the part. Unless specifically noted, NOP will represent both NOP and DESL command in later descriptions.

\*5. BST is effective after READ command is issued.

\*6. READ, READA, WRIT and WRITA commands should only be issued after the corresponding bank has been activated (ACTV command). Refer to "■ STATE DIAGRAM".

- \*7. ACTV command should only be issued after corresponding bank has been page closed by PRE or PALL command.
- \*8. Either PRE or PALL command and MRS or EMRS command are required after power up.
- \*9. MRS or EMRS command should only be issued after all banks have been page closed (PRE or PALL command), and DQs are in Hi-Z. Refer to "■ STATE DIAGRAM".

\*10. Refer to"■ MODE REGISTER TABLE".

Function	Command	CI	ΚE	DM₀	DM <sub>1</sub>	DM <sub>2</sub>	DM₃	
	Command	(n - 1)	(n)			DIVIZ		
Data Mask for DQ <sub>0</sub> to DQ <sub>7</sub>	MASK0	Н	Х	Н	Х	Х	Х	
Data Mask for DQ8 to DQ15	MASK1	Н	Х	Х	Н	Х	Х	
Data Mask for DQ16 to DQ23	MASK2	Н	Х	Х	Х	Н	Х	
Data Mask for DQ24 to DQ31	MASK3	Н	Х	Х	Х	Х	Н	

#### DM TRUTH TABLE (Effective during Write mode)

#### **CKE TRUTH TABLE**

Current	From a time	Natas	0	CK	Έ	00		0.4.0			BA <sub>0</sub>	A <sub>0</sub>	DQ <sub>0</sub>
State	Function	Notes	Command	(n-1)	(n)	CS	RAS	CAS	WE	AP	to BA <sub>2</sub>	to A <sub>10</sub>	to DQ <sub>31</sub>
Idle	Auto-refresh	*11	REF	Н	Н	L	L	L	Н	Х	Х	Х	—
Idle	Self-refresh Entry	/ *11 / *12	SELF	Н	L	L	L	L	Н	Х	х	Х	Hi-Z
Self- refresh	Self-refresh Cont	inue	—	L	L	Х	х	Х	Х	Х	Х	Х	Hi-Z
Self-	Self-refresh Exit		SELFX	L	Н	L	Н	Н	Н	Х	Х	Х	Hi-Z
refresh	Sell-reliesh LXI			L	Н	Н	Х	Х	Х	Х	Х	Х	Hi-Z
Idle	Power Down Ent	ry *13	PDEN	Н	L	L	Н	Н	Н	Х	Х	Х	Hi-Z
luie	Fower Down Lift	iy 13	FULN	Н	L	Н	Х	Х	Х	Х	Х	Х	Hi-Z
Power Down	Power Down Cor	ntinue	_	L	L	Х	x	х	Х	Х	х	х	Hi-Z
Power	Power Down Exit		PDEX	L	Н	L	Н	Н	Н	Х	Х	Х	Hi-Z
Down			FDEA	L	Н	Η	Х	Х	Х	Х	Х	Х	Hi-Z

\*11: The REF and SELF commands should only be issued after all banks have been precharged (PRE or PALL command). In case of SELF command, it should also be issued after the last read data have been appeared on DQ. Refer to "■ STATE DIAGRAM".

\*12: CKE must bring to Low level together with REF command.

\*13: The PDEN command should only be issued after the last read data have been appeared on DQ and after the IDPL is satisfied from last write data input.

Current State	CS	RAS	CAS	WE	Address	Command	Function	Notes
	Н	Х	Х	Х	Х	DESL	NOP	
	L	Н	Н	Н	Х	NOP	NOP	
	L	Н	Н	L	Х	BST	NOP	*15
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*16
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*16
Idle	L	L	Н	Н	BA, RA	ACTV	Bank Active after IRCD	
	L	L	Н	L	BA, AP	PRE	NOP	
	L	L	Н	L	BA, AP	PALL	NOP	*15
	L	L	L	Н	Х	REF/SELF	Auto-refresh or Self-refresh	*17
	L	L	L	L	MODE	MRS	Mode Register Set (Idle after Imrd)	*17
	Н	Х	Х	Х	Х	DESL	NOP	
	L	Н	Н	Н	Х	NOP	NOP	
	L	Н	Н	L	Х	BST	NOP	*15
	L	Н	L	Н	BA, CA, AP	READ/READA	Begin Read; Determine AP	
Bank Active	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Begin Write; Determine AP	
Dank Active	L	L	Н	Н	BA, RA	ACTV	Illegal	*16
	L	L	Н	L	BA, AP	PRE	Precharge	
	L	L	Н	L	BA, AP	PALL	Precharge	*15
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

## **OPERATION COMMAND TABLE (Applicable to single bank)(Note\*13)**

Current State	CS	RAS	CAS	WE	Address	Command	Function Notes
	Н	Х	х	Х	Х	DESL	NOP (Continue Burst to End $\rightarrow$ Bank Active)
	L	н	н	Н	Х	NOP	NOP (Continue Burst to End $\rightarrow$ Bank Active)
	L	Н	Н	L	Х	BST	Terminate Burst $\rightarrow$ Bank Active
Read	L	н	L	Н	BA, CA, AP	READ/READA	Terminate Burst, New Read; Determine AP
Neau	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal
	L	L	Н	Н	BA, RA	ACTV	Illegal *16
	L	L	Н	L	BA, AP	PRE	Terminate Burst, Precharge
	L	L	Н	L	BA, AP	PALL	Terminate Burst, Precharge *15
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal
	н	х	х	Х	х	DESL	NOP (Continue Burst to End $\rightarrow$ Write Recovering)
	L	н	н	Н	х	NOP	NOP (Continue Burst to End $\rightarrow$ Write Recovering)
	L	Н	Н	L	Х	BST	Illegal
	L	н	L	Н	BA, CA, AP	READ/READA	Terminate Burst, Start Read; *20 Determine AP
Write	L	н	L	L	BA, CA, AP	WRIT/WRITA	Terminate Burst, New Write; Determine AP
	L	L	Н	Н	BA, RA	ACTV	Illegal *16
	L	L	Н	L	BA, AP	PRE	Terminate Burst, Precharge *18
	L	L	Н	L	BA, AP	PALL	Terminate Burst, Precharge *15, *18
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal

Current State	CS	RAS	CAS	WE	Address	Command	Function Notes
	н	х	Х	Х	Х	DESL	NOP (Continue Burst to End $\rightarrow$ Precharge)
	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End $\rightarrow$ Precharge)
	L	Н	Н	L	Х	BST	Illegal
Read With	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal *16
Auto- Precharge	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal
Flechalge	L	L	Н	Н	BA, RA	ACTV	Illegal *16
	L	L	Н	L	BA, AP	PRE	Illegal *16
	L	L	Н	L	BA, AP	PALL	Illegal
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal
	н	х	х	Х	х	DESL	NOP (Continue Burst to End $\rightarrow$ Write Recovering with Precharge)
	L	н	Н	Н	Х	NOP	NOP (Continue Burst to End $\rightarrow$ Write Recovering with Precharge)
	L	Н	Н	L	Х	BST	Illegal
Write with	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal
Auto Precharge	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal *16
Flechalge	L	L	Н	Н	BA, RA	ACTV	Illegal *16
	L	L	Н	L	BA, AP	PRE	Illegal *16
	L	L	Н	L	BA, AP	PALL	Illegal
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal

<b>OPERATION COMMAND TABLE (Continued</b>	1)	
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Current State	CS	RAS	CAS	WE	Address	Command	Function	Notes
	Н	Х	Х	Х	Х	DESL	NOP (Idle after IRP)	
	L	Н	Н	Н	Х	NOP	NOP (Idle after IRP)	
	L	Н	Н	L	Х	BST	NOP (Idle after IRP)	*15
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*16
Procharging	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*16
Precharging	L	L	Н	Н	BA, RA	ACTV	Illegal	*16
	L	L	Н	L	BA, AP	PRE	NOP	*16
	L	L	Н	L	BA, AP	PALL	NOP	*15
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
	Н	Х	Х	Х	Х	DESL	NOP (Bank Active after IRCD)	
	L	Н	Н	Н	Х	NOP	NOP (Bank Active after IRCD)	
	L	Н	Н	L	Х	BST	NOP (Bank Active after IRCD)	*15
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*16
Bank	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*16
Activating	L	L	Н	Н	BA, RA	ACTV	Illegal	*19
	L	L	Н	L	BA, AP	PRE	Illegal	*16
	L	L	Н	L	BA, AP	PALL	Illegal	
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

Current State	CS	RAS	CAS	WE	Address	Command	Function	Notes
	Н	Х	Х	Х	Х	DESL	NOP (Bank Active after Iwrd)	
	L	н	Н	Н	Х	NOP	NOP (Bank Active after Iwrd)	
	L	н	Н	L	Х	BST	NOP (Bank Active after Iwrd)	*15
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*16
Write	L	Н	L	L	BA, CA, AP	WRIT/WRITA	New Write; Determine AP	
Recovering	L	L	Н	Н	BA, RA	ACTV	Illegal	*16
	L	L	Н	L	BA, AP	PRE	Illegal	*16
	L	L	Н	L	BA, AP	PALL	Illegal	
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
	Н	Х	Х	Х	Х	DESL	NOP (Idle after IwaL)	
	L	Н	Н	Н	Х	NOP	NOP (Idle after IwaL)	
	L	Н	Н	L	Х	BST	Illegal	
Write	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*16
Recovering	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*16
with Auto-	L	L	Н	Н	BA, RA	ACTV	Illegal	*16
precharge	L	L	Н	L	BA, AP	PRE	Illegal	*16
	L	L	Н	L	BA, AP	PALL	Illegal	
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
	Н	Х	Х	Х	Х	DESL	NOP (Idle after IRFC)	
	L	Н	Н	Х	Х	NOP/BST	NOP (Idle after IRFC)	
Refreshing	L	н	L	Х	Х	READ/READA/ WRIT/WRITA	Illegal	
	L	L	Н	Х	Х	ACTV/ PRE/PALL	Illegal	
	L	L	L	Х	Х	REF/SELF/ MRS	Illegal	

Current State	CS	RAS	CAS	WE	Address	Command	Function Notes
	Н	Х	Х	Х	Х	DESL	NOP (Idle after Imrd)
	L	Н	Н	Н	Х	NOP	NOP (Idle after Imrd)
Mode	L	Н	Н	L	Х	BST	Illegal
Register Setting	L	Н	L	Х	Х	READ/READA/ WRIT/WRITA	Illegal
	L	L	х	х	х	ACTV/PRE/ PALL/REF/ SELF/MRS	Illegal

 Abbreviations:
 RA = Row Address
 BA = Bank Address

CA = Column Address AP = Auto Precharge

Notes: \*14. All entries assume the CKE was High during the proceeding clock cycle and the current clock cycle. \*15. Entry may affect other banks.

- \*16. Illegal to bank in specified state; entry may be legal in the bank specified by BA, depending on the state of that bank.
- \*17. Illegal if any bank is not idle.
- \*18. Must mask preceding data that don't satisfy IDPL.
- \*19. Legal if other bank specified in BA is idle state and IRRD is satisfied for that bank.
- \*20. Must mask preceding data that don't satisfy IWRD.

#### COMMAND TRUTH TABLE FOR CKE

Current State	CKE (n-1)	CKE (n)	CS	RAS	CAS	WE	Address	Function Notes
	Н	Х	Х	Х	Х	Х	Х	Invalid
	L	Н	н	x	х	х	x	Exit Self-refresh (Self-refresh Recovery → Idle after t <sub>PDEX</sub> + I <sub>SCD</sub> or I <sub>XSNR</sub> )
Self- refresh	L	Н	L	н	н	Н	x	Exit Self-refresh (Self-refresh Recovery → Idle after tPdex + Iscd or Ixsnr)
	L	Н	L	Н	Н	L	Х	Illegal
	L	н	L	Н	L	Х	Х	Illegal
	L	Н	L	L	Х	Х	Х	Illegal
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Self-refresh)
	L	Х	Х	Х	Х	Х	Х	Invalid
	Н	Н	Н	Х	Х	Х	Х	Idle after Iscd or Ixsnr
Self-	Н	Н	L	Н	Н	Н	Х	Idle after Iscd or Ixsnr
refresh	Н	Н	L	Н	Н	L	Х	Illegal
Recovery	Н	Н	L	Н	L	Х	Х	Illegal
	Н	Н	L	L	Х	Х	Х	Illegal
	Н	L	Х	Х	Х	Х	Х	Illegal
	Н	Х	Х	Х	Х	Х	Х	Invalid
	L	Н	Н	х	Х	Х	х	Power Down Exit $\rightarrow$ Return to original state after tPDEX
Power	L	Н	L	н	Н	Н	х	Power Down Exit $\rightarrow$ Return to original state after tPDEX
Down	L	Н	L	Н	Н	L	Х	Illegal
	L	Н	L	Н	L	Х	Х	Illegal
	L	Н	L	L	Х	Х	Х	Illegal
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Power Down Mode)

Current State	CKE (n-1)	CKE (n)	CS	RAS	CAS	WE	Address	Function Notes
	Н	Н	Н	Х	Х	Х	Х	NOP
	Н	Н	L	Н	Х	Х	V	Refer to the Command Truth Table.
	Н	Н	L	L	Н	Х	V	Refer to the Command Truth Table.
	Н	Н	L	L	L	Н	Х	Auto-refresh
	Н	Н	L	L	L	L	V	Mode Register Set *21
All	Н	L	Н	Х	Х	Х	Х	Power Down Entry *22
Banks	Н	L	L	Н	Н	Н	Х	Power Down Entry *22
Idle	Н	L	L	Н	Н	L	Х	Illegal
	Н	L	L	Н	L	Х	Х	Illegal
	Н	L	L	L	Н	Х	Х	Illegal
	Н	L	L	L	L	Н	Х	Self-refresh Entry *22
	Н	L	L	L	L	L	Х	Illegal
	L	Х	Х	Х	Х	Х	Х	Invalid
	Н	Н	Х	Х	Х	Х	Х	Refer to the Command Truth Table.
Bank Active	Н	L	Х	Х	Х	Х	Х	Illegal
	L	Н	Х	Х	Х	Х	Х	Invalid
	L	L	Х	Х	Х	Х	Х	Invalid

## COMMAND TRUTH TABLE FOR CKE (continued)

Current State	CKE (n-1)	CKE (n)	CS	RAS	CAS	WE	Address	Function Notes
Bank	Н	Н	Х	Х	Х	Х	Х	Refer to the Command Truth Table.
Activating, Read, Write,	Н	L	Х	Х	Х	Х	Х	Illegal *23
Write Recovering, Precharging	L	Н	Х	Х	Х	Х	Х	Invalid
	L	L	Х	Х	Х	Х	Х	Invalid
Any State	L	Х	Х	Х	Х	Х	Х	Invalid
Other Than	Н	Н	Х	Х	Х	Х	Х	Refer to the Command Truth Table.
Listed Above	Н	L	Х	Х	Х	Х	Х	Illegal *23
	Н	L	Н	L	L	L	Х	Illegal
	Н	L	L	Н	Н	Н	Х	Illegal
	Н	L	L	Н	Н	L	Х	Illegal
Refresh	Н	L	L	Н	L	Х	Х	Illegal
Reliesii	Н	L	L	L	Х	Х	Х	Illegal
	L	L	Х	Х	Х	Х	Х	Invalid
	L	Н	Х	Х	Х	Х	Х	Invalid
	Н	Н	Х	Х	Х	Х	Х	Refer to the Command Truth Table.

## COMMAND TRUTH TABLE FOR CKE (continued)

Notes: \*21. Refer to "■ MODE REGISTER TABLE".

\*22. PDEN and SELF command should only be issued after the last read data have been appeared on DQ.

\*23. The Clock Suspend mode is not supported on this device and it is illegal if CKE is brought to Low during the Burst Read or Write mode.

## MB81P643287-50/-60

### ■ STATE DIAGRAM

MINIMUM CLOCK LATENCY OR DELAY TIME FOR SINGLE BANK OPERATION

			•••••				=				
Second command (same bank) First command	MRS	ACTV	READ	READA	WRIT	WRITA	BST	™ PRE	PALL	REF	SELF
MRS	Imrd	Imrd					Imrd	Imrd	Imrd	Imrd	Imrd
ACTV			Ircd	*4 Ircd	Ircd	*4 Ircd	1	Iras	IRAS		
READ			1	* 4 1	* 3 Irwd	*3, 4 <b>I</b> RWD	1	*4 1	*4 1		
READA	*5, 6 BL/2 + I <sub>RP</sub>	BL/2 + Irp						*₄ BL/2 + I <sub>RP</sub>	*4 BL/2 + I <sub>RP</sub>	*6 BL/2 + I <sub>RP</sub>	*5, 6 BL/2 + Irp
WRIT			*7 Iwrd	*4, 7 Iwrd	1	* 4 1		*4,7 Idpl	*4,7 Idpl		
WRITA	*6 Iwal	Iwal						*4 Iwal	*4 Iwal	*6 Iwal	*6 Iwal
BST			1	1	*3 Ibsnc	*3 Ibsnc	1	*4 1	*4 1		
PRE	*5, 6 IRP	IRP					1	1	*4 1	*6 Irp	*5, 6  RP
PALL	*5 Irpa	Irpa					1	1	1	Irpa	*5 Irpa
REF	Irfc	Irfc					Irfc	Irfc	Irfc	Irfc	Irfc
SELFX	Ixsnr	Ixsnr					Ixsnr	Ixsnr	Ixsnr	Ixsnr	Ixsnr

Notes: \*1. BL/2 = tck  $\times$  BL / 2. (Example: In case of BL = 4, BL/2 means 2 clocks.)

\*2. Assume PALL command does not affect any operation on the other bank(s).

\*3. Assume no I/O conflict.

\*4. IRAS must be satisfied.

\*5. Assume all outputs are in High-Z state.

\*6. Assume all other banks are in idle state.

\*7. IDPL and IWRD are specified from last data input and assumed preceding pair of write data are masked by DM<sub>0</sub> to DM<sub>3</sub> input.



Illegal Command

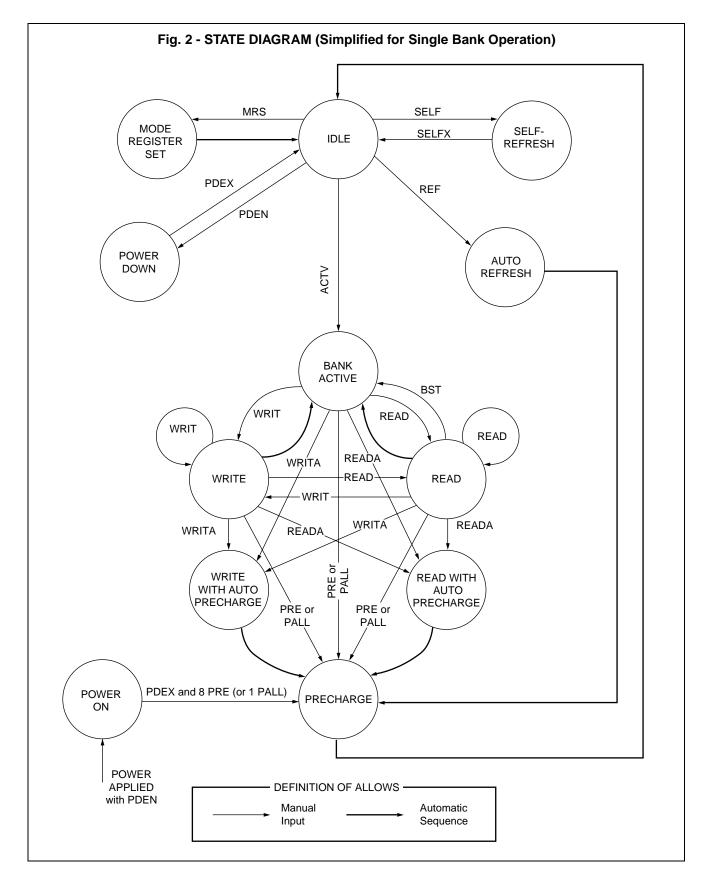
Second command											
(other bank)			*8	*8	*8	*8	*9	*2, 9			
(Othor Damt) *10	MRS	ACTV	READ	READA	WRIT	WRITA	BST	PRE	PALL	REF	SELF
First command							501				
MRS	Imrd	Imrd					Imrd	Imrd	Imrd	Imrd	Imrd
ACTV		*6 Irrd	*11 <b>1</b>	*11 <b>1</b>	*11 <b>1</b>	*11 <b>1</b>	*11 <b>1</b>	1	Iras		
READ		*6 1	1	1	* 3 Irwd	*3 Irwd	1	1	*4 1		
READA	*5, 6 BL/2+ I <sub>RP</sub>	*6 1	*4 1	*4	* 3, 4 Irwd	* 3, 4 IRWD		1	BL/2+ Irp	*6 BL/2+ I <sub>RP</sub>	*5, 6 BL/2+ I <sub>RP</sub>
WRIT		*6 1	*7 Iwrd	*7 Iwrd	1	1		1	*4,7 Idpl		
WRITA	*6 Iwal	*6 1	*4 BL/2 + Iwrd	*4 BL/2 + Iwrd	*4 1	*4 1		1	Iwal	*6 Iwal	*6 Iwal
BST		*6 1	*11 <b>1</b>	*11 <b>1</b>	*3, 11 Ibsnc	*3, 11 Ibsnc	1	1	*4 1		
PRE	*5, 6 IRP	*6 1	*11 <b>1</b>	*11 <b>1</b>	*3, 11 <b>1</b>	*3, 11 <b>1</b>	*11 <b>1</b>	1	*4 1	*6 RP	*5, 6 IRP
PALL	*5 Irpa	Irpa					1	1	1	Irpa	*5 Irpa
REF	Irfc	Irfc					Irfc	Irfc	Irfc	Irfc	Irfc
SELFX	Ixsnr	Ixsnr					Ixsnr	Ixsnr	Ixsnr	Ixsnr	Ixsnr

## MB81P643287-50/-60

Notes: \*1.  $BL/2 = t_{CK} \times BL / 2$ . (Example: In case of BL = 4, BL/2 means 2 clocks.)

- \*2. Assume PALL command does not affect any operation on the other bank(s).
- \*3. Assume no I/O conflict.
- \*4. IRAS must be satisfied.
- \*5. Assume all outputs are in High-Z state.
- \*6. Assume the other bank(s) is in idle state.
- \*7. IDPL and IWRD are specified from last data input and assumed preceding pair of write data are masked by DM<sub>0</sub> to DM<sub>3</sub> input.
- \*8. Assume the other bank(s) is in active state and IRCD is satisfied.
- \*9. Assume the other bank(s) is in active state and IRAS is satisfied.
- \*10. Second command have to follow the minimum clock latency or delay time of single bank operation in other bank (second command is asserted.)
- \*11. Assume other banks are not in READA/WRITA state.

Illegal Command.



## FUNCTIONAL DESCRIPTION

#### DDR, Double Data Rate Function

The regular SDRAM read and write cycle have only used the rising edge of external clock input. When clock signal goes to High from Low at the read mode, the read out data will be available at every rising clock edge after the specified latency up to burst length. The MB81P643287 DDR FCRAM features a twice of data transfer rate within a same clock period by transferring data at every rising and falling clock edge. Refer to Figure 3.

#### FCRAM™

The MB81P643287 utilizes FCRAM core technology. The FCRAM is an acronym of Fast Cycle Random Access Memory and provides very fast random cycle time, low latency and low power consumption than regular DRAMs.

#### CLOCK INPUT (CLK, CLK)

The MB81P643287 adopts differential clock scheme. CLK is a master clock and its rising edge is used to latch all command and address inputs. CLK is a complementary clock input.

The MB81P643287 implements Delay Locked Loop (DLL) circuit. This internal DLL tracks the signal cross point between CLK and CLK and generate some clock cycle delay for the output buffer control at Read mode.

The internal DLL circuit requires some Lock-on time for the stable delay time generation. In order to stabilize the delay, a constant stable clock input for IPCD period is required during the Power-up initialization and a constant stable clock input for ISCD period is also required after Self-refresh exit as specified ISCD prior to the any command.

#### **POWER DOWN (CKE)**

CKE is a synchronous input signal and enables power down mode.

When all banks are in idle state, CKE controls Power Down (PD) and Self-refresh mode. The PD and Self-refresh is entered when CKE is brought to Low and exited when it returns to High.

During the Power Down and Self-refresh mode, both CLK and CLK are disabled after specified time.

CKE does not have a Clock Suspend function unlike CKE pin of regular SDRAMs, and it is illegal to bring CKE into Low if any read or write operation is being performed. For the detail, refer to Timing Diagrams.

It is recommended to maintain CKE to be Low until  $V_{DD}$  gets in the specified operating range in order to assure the power-up initialization.

### CHIP SELECT (CS)

CS enables all commands inputs, RAS, CAS, and WE, and address input. When CS is High, all command signals are negated but internal operation such as burst cycle will not be suspended.

#### COMMAND INPUTS (RAS, CAS and WE)

As well as regular SDRAMs, each combination of RAS, CAS and WE input in conjunction with CS input at a rising edge of the CLK determines SDRAM operation. Refer to "■FUNCTION TRUTH TABLE".

#### BANK ADDRESS (BA<sub>0</sub> to BA<sub>2</sub>)

The MB81P643287 has eight internal banks and each bank is organized as 256K words by 32-bit. Bank selection by BA occurs at Bank Active command (ACTV) followed by read (READ or READA), write (WRIT or WRITA), and Precharge(PRE) command.

#### ADDRESS INPUTS (Ao to A10)

Address input selects an arbitrary location of a total of 2,097,152 words of each memory cell matrix within each bank. A total of twenty address input signals are required to decode such a matrix. DDR SDRAM adopts an address multiplexer in order to reduce the pin count of the address line. At a Bank Active command (ACTV), eleven Row addresses are initially latched as well as three Bank addresses and the remainder of seven Column addresses are then latched by a Column address strobe command of either a read command (READ or READA) or write command (WRIT or WRITA).

#### DATA STROBE (DQS<sub>0</sub> to DQS<sub>3</sub>)

DQS<sub>0</sub> to DQS<sub>3</sub> are bi-directional signal and represent byte 0 to byte 3, respectively. During Read operation, DQS<sub>0</sub> to DQS<sub>3</sub> provides the read data strobe signal that is intended to use input data strobe signal at the receiver circuit of the controller(s). It turns Low before first data is coming out and toggle High to Low or Low to High till end of burst read. Refer to Figure 3 for the timing example.

The CAS Latency is specified to the first Low to High transition of these DQS<sub>0</sub> to DQS<sub>3</sub> output.

During the write operation,  $DQS_0$  to  $DQS_3$  are used to latch write data and Data Mask signals. As well as the behavior of read data strobe, the first rising edge of  $DQS_0$  to  $DQS_3$  input latches first input data and following falling edge of  $DQS_0$  to  $DQS_3$  to  $DQS_3$  signal latches second input data. This sequence shall be continued till end of burst count. Therefore,  $DQS_0$  to  $DQS_3$  must be provided from controller that drives write data.

Note that DQS<sub>0</sub> to DQS<sub>3</sub> input signal should not be tristated from High at the end of write mode.

#### DATA INPUTS AND OUTPUTS (DQ0 to DQ31)

Input data is latched by DQS<sub>0</sub> to DQS<sub>3</sub> input signal and written into memory at the clock following the write command input. Output data is obtained together with DQS<sub>0</sub> to DQS<sub>3</sub> output signals at programmed read CAS latency.

The polarity of the output data is identical to that of the input. Data is valid after DQS<sub>0</sub> to DQS<sub>3</sub> output signal transitions ( $t_{QSQ}$ ) as specified in Data Valid Time ( $t_{DV}$ ).

#### WRITE DATA MASK (DMo to DM3)

 $DM_0$  to  $DM_3$  are active High enable inputs and represent byte 0 to byte 3 respectively.  $DM_0$  to  $DM_3$  have a data input mask function, and are also sampled by  $DQS_0$  to  $DQS_3$  input signal together with input data. During write cycle,  $DM_0$  to  $DM_3$  provide byte mask function. When DMx = High is latched by a  $DQS_0$  to  $DQS_3$  signal edge, data input at the same edge of  $DQS_0$  to  $DQS_3$  is masked.

During read cycle, all  $DM_0$  to  $DM_3$  are inactive and do not have any effect on read operation. Refer to  $DM_0$  to  $DM_3$  TRUTH TABLE.

#### BURST MODE OPERATION AND BURST TYPE

The burst mode provides faster memory access and MB81P643287 read and write operations are burst oriented. The burst mode is implemented by keeping the same Row address and by automatic strobing Column address in every single clock edge till programmed burst length(BL). Access time of burst mode is specified as t<sub>ACC</sub>. The internal column address counter operation is determined by a mode register which defines burst type(BT) and burst count length(BL) of 2, 4 or 8 bits of boundary. In order to terminate or to move from the current burst mode to the next stage while the remaining burst count is more than 2, the following combinations will be required.

Current Stage	Next Stage	N	Method (Assert the following command)					
Burst Read	Burst Read	Read Commar	nd					
Burst Read	Burst Write	1st Step	Burst Stop Command (BST)					
Buist Reau	Buist White	2nd Step	Write Command after IBSNC					
Burst Write	Burst Write	Write Command						
Burst Write	Burst Read	1st Step	Data Mask Input					
Duist write	Buist Reau	2nd Step	Read Command after IwRD from last data input					
Burst Read	Precharge	Precharge Cor	nmand					
Burst Write	Prochargo	1st Step	Data Mask Input					
Buist White	Precharge	2nd Step	Precharge Command after IDPL from last data input					

The burst type is sequential only. The sequential mode is an incremental decoding scheme within a boundary address to be determined by count length, it assigns +1 to the previous (or initial) address until reaching the end of boundary address and then wraps round to the least significant address(= 0). If the first access of column address is even (0), the next address will be odd (1), or vice-versa.

Burst Length	Starting Column Address A <sub>2</sub> A <sub>1</sub> A <sub>0</sub>	Sequential Mode
2	X X 0	0 – 1
2	X X 1	1 – 0
	X 0 0	0-1-2-3
4	X 0 1	1-2-3-0
4	X 1 0	2-3-0-1
	X 1 1	3-0-1-2
	0 0 0	0-1-2-3-4-5-6-7
	0 0 1	1-2-3-4-5-6-7-0
	0 1 0	2 - 3 - 4 - 5 - 6 - 7 - 0 - 1
8	0 1 1	3-4-5-6-7-0-1-2
0	1 0 0	4-5-6-7-0-1-2-3
	1 0 1	5-6-7-0-1-2-3-4
	1 1 0	6-7-0-1-2-3-4-5
	1 1 1	7-0-1-2-3-4-5-6

#### **BURST STOP COMMAND (BST)**

The Burst Stop command (BST) terminates the burst read operation except for a case that Auto-precharge option is asserted. When the BST command is issued during the burst read operation, the all output buffers, DQs and DQS<sub>0</sub> to DQS<sub>3</sub>, will turn to High-Z state after some latencies that to be matched with programmed CAS latency and internal bank state remains active state.

In a case of terminating the burst write operation, <u>the BST command should not be issued at any time during</u> <u>burst write operation</u>. Refer to previous page for the write interrupt and termination rule.

#### PRECHARGE AND PRECHARGE OPTION (PRE, PALL)

The DDR SDRAM memory core is the same as conventional DRAMs', requiring precharge and refresh operations. Precharge rewrites the bit line and to reset the internal Row address line and is executed by the precharge operation (PRE or PALL). With the precharge operation, DDR SDRAM will automatically be in standby state after specified precharge time (I<sub>RP</sub>, I<sub>RPA</sub>).

The precharged bank is selected by combination of AP and bank address (BA) when precharge command is issued. If AP = High, all banks are precharged regardless of BA (PALL command). If AP = Low, a bank to be selected by BA is precharged (PRE command).

The auto-precharge enters precharge mode at the end of burst mode of read or write without Precharge command issue. This auto-precharge is entered by AP = High when a Read (READ) or Write (WRIT) command is issued. Applying BST is illegal if the Auto-precharge option is used.

Refer to "■FUNCTION TRUTH TABLE".

#### **AUTO-REFRESH (REF)**

Auto-refresh uses the internal refresh address counter. The MB81P643287 Auto-refresh command (REF) automatically generates Bank Active and Precharge command internally. All banks of SDRAM should be precharged prior to the Auto-refresh command. The Auto-refresh command should also be issued within every 8  $\mu$ s period.

#### SELF-REFRESH ENTRY (SELF)

Self-refresh function provides automatic refresh by an internal timer as well as Auto-refresh and will continue the refresh operation until cancelled by SELFX.

The Self-refresh mode is entered by applying an Auto-refresh command in conjunction with CKE = Low (SELF). Once MB81P643287 enters the self-refresh mode, all inputs except for CKE can be either logic high or low level state and outputs will be in a High-Z state. During Self-refresh mode, CKE = Low should be maintained. SELF command should only be issued after last read data has been appeared on DQ.

Note: When the burst refresh method is used, a total of 4096 auto-refresh commands within 4 ms must be asserted prior to the self-refresh mode entry.

#### SELF-REFRESH EXIT (SELFX)

To exit Self-refresh mode, CKE must bring to High for at least 2 clock cycles together with NOP condition. Refer to Timing Diagram for the detail procedure. It is recommended to issue at least one Auto-refresh command just after the IRFC period to avoid the violation of refresh period.

- WARNING: A stable clock for I<sub>SCD</sub> period with a constant duty cycle must be supplied prior to applying any read command to insure the DLL is locked against the latest device conditions.
- Note: When the burst refresh method is used, a total of 4096 auto-refresh commands within 4 ms must be asserted both before the self-refresh entry and after the self-refresh exit.

#### MODE REGISTER SET (MRS)

The mode register of SDRAM provides a variety of different operations. The register consists of four operation fields; Burst Length, Burst Type, CAS Latency, and Test Mode Entry (This Test Mode Entry must not be used). Refer to MODE REGISTER TABLE.

The mode register can be programmed by the Mode Register Set command (MRS). Each field is set by the address line. Once a mode register is programmed, the contents of the register will be held until re-programmed by another MRS command (or part loses power). MRS command should only be issued on condition that all banks are in idle state and all DQS are in High-Z. The condition of the mode register is undefined after the power-up stage. It is required to set each field at power-up initialization.

Refer to POWER-UP INITIALIZATION below.

Note: The Extended Mode Register Set command (EMRS) and its DLL Enable function of EMRS field is only used at power-on sequence.

#### **POWER-UP INITIALIZATION**

The MB81P643287 internal condition at and after power-up will be undefined. It is required to follow the following Power On Sequence to execute read or write operation.

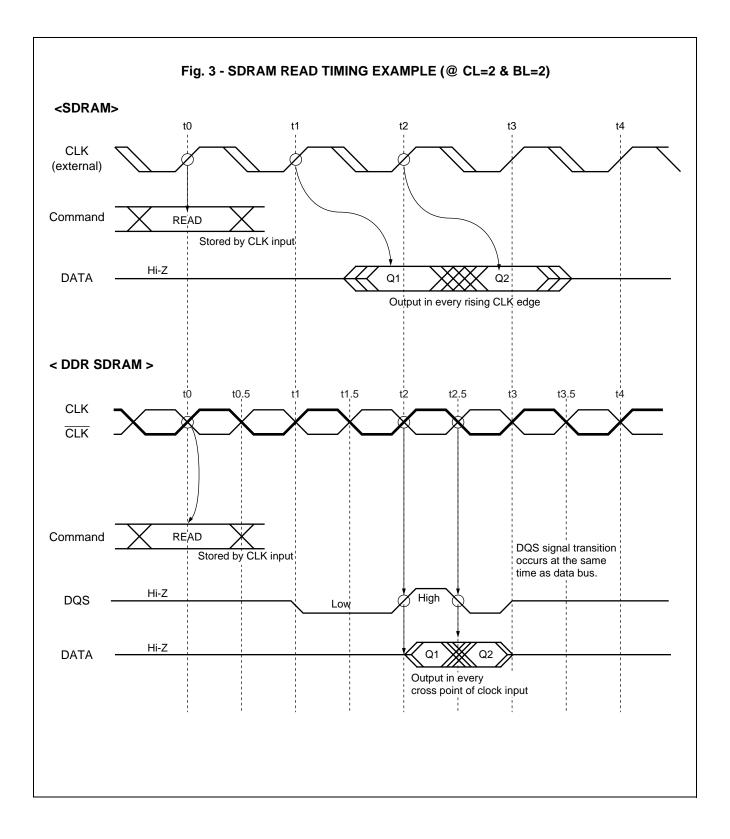
- 1. Apply V<sub>DD</sub> voltage to all V<sub>DD</sub> pins before or at the same time as V<sub>DDQ</sub> pins and attempt to maintain all input signals to be Low state (or at least CKE to be Low state).
- 2. Apply VDD voltage to all VDDQ pins before or at the same time as VREF and VTT.
- 3. Apply VREF and VTT. (VTT is applied to the system).
- 4. Start clock after all power supplies reached in a specified operating range and maintain stable condition for a minimum of 200 μs.
- 5. After the minimum of 200  $\mu$ s stable power and clock, apply NOP condition and take CKE to be High state.
- 6. Issue Precharge All Banks (PALL) command or Precharge Single Bank (PRE) command to every banks.
- 7. Issue EMRS to enable DLL, DE = Low.
- 8. Issue Mode Register Set command (MRS) to reset DLL, DR = High. An additional clock input for IPCD\*1 period is required to lock the DLL.
- 9. Apply minimum of two Auto-refresh command (REF).\*2
- 10. Program the mode register by Mode Register Set command (MRS) with DR = Low.\*2
- \*1: The IPCD depends on operating clock period. The IPCD is counted from "DLL Reset" at step-8 to any command input at step-10.
- \*2: The Mode Register Set command (MRS) can be issued before two Auto-refresh cycle.

#### **POWER-DOWN**

The MB81P643287 uses multiple power supply voltage. It is required to follow the reversed sequence of above Power On Sequence.

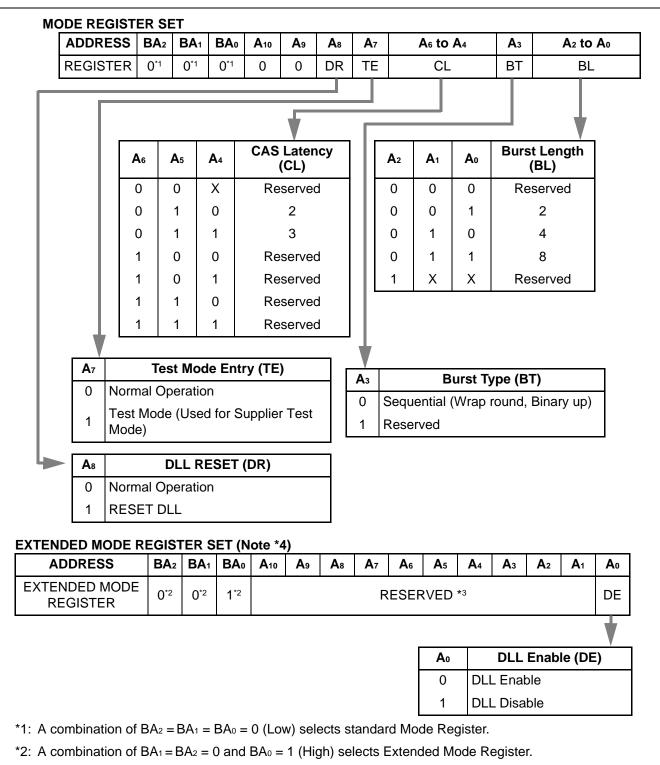
- 1. Take all input signals to be Vss or High-Z.
- 2. Deapply VDDQ.
- 3. Deapply VDD at the same time as VDDQ.

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### MODE REGISTER TABLE



\*3: These RESERVED field in EMRS must be set as 0.

## ■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

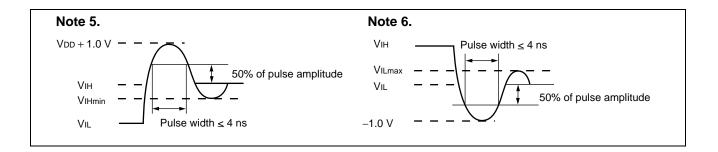
Parameter	Symbol	Value	Unit
Voltage of $V_{DD}$ Supply Relative to $V_{SS}$	Vdd, Vddq	-0.5 to +3.6	V
Voltage at Any Pin Relative to Vss	Vin, Vout	-0.5 to +3.6	V
Short Circuit Output Current	Іоит	±50	mA
Power Dissipation	PD	2.0	W
Storage Temperature	Тѕтс	-55 to +125	°C

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

## RECOMMENDED OPERATING CONDITIONS

#### (Referenced to Vss)

Parameter N	otes	Symbol	Min.	Тур.	Max.	Unit
		Vdd	2.3	2.5	2.7	V
Supply Voltage		Vddq	Vdd	Vdd	Vdd	V
		Vss, Vssq	0	0	0	V
Input Reference Voltage	*1	Vref	$V_{\text{DDQ}} \times  0.49$	$V_{\text{DDQ}}  \times 0.5$	$V_{DDQ}  imes 0.51$	V
Termination Voltage	*2	Vtt	Vref - 0.04	Vref	Vref + 0.04	V
Single Ended SSTL DC Level Input High Voltage	*3	VIH (DC)	Vref + 0.25	_	VDDQ + 0.1	V
Single Ended SSTL DC Level Input Low Voltage	*3	VIL (DC)	- 0.1	_	Vref - 0.25	V
Single Ended SSTL AC Level Input High Voltage	*3, *5	VIH (AC)	Vref + 0.35	_	—	V
Single Ended SSTL AC Level Input Low Voltage	*3, *5	VIL (AC)	—	_	Vref - 0.35	V
Differential DC Level Input Voltage Range	*3	VIN (DC)	- 0.1	_	VDDQ + 0.1	V
Differential DC Level Differential Input Voltage	*3	VSWING (DC)	0.5	_	VDDQ + 0.2	V
Differential AC Level Differential Input Voltage	*3	VSWING (AC)	0.7	_	—	V
Differential AC Level Input Crosspoint Voltage	*3	Vx (AC)	Vddq/2 - 0.2	Vddq/2	VDDQ/2 + 0.2	V
Differential Input Signal Offset Voltage	*4	VISO (AC)	Vddq/2 - 0.2	Vddq/2	VDDQ/2 + 0.2	V
Termination Resistor (SSTL I/Os)	*2	R⊤	—	50	—	Ω
Ambient Temperature		TA	0	_	70	°C

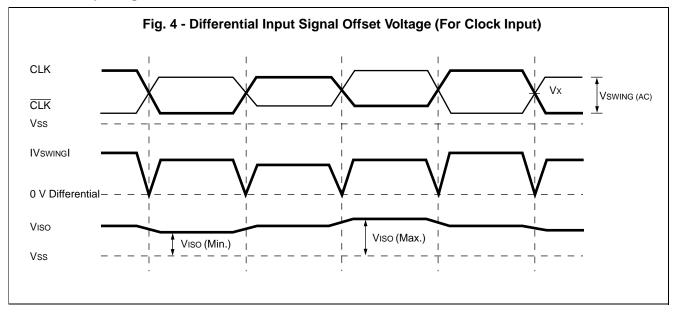


- Notes: \*1. VREF is expected to track variations in the DC level of VDDQ of the transmitting device. Peak-to-Peak noise level on VREF may not exceed ± 2% of the supplied DC value.
  - \*2. V<sub>TT</sub> is used for SSTL\_2 bus and is not applied to the device. V<sub>TT</sub> is expected to be set equal to V<sub>REF</sub> and must be track variations in the DC level of V<sub>REF</sub>.
  - \*3. Applicable when signal(s) is terminated to the  $V\pi$  of SSTL\_2 bus.
  - \*4. VISO means {VIN(CLK) + VIN(CLK)} / 2. Refer to Differential Input Signal Definition.
  - \*5. Overshoot limit: V<sub>IH</sub> (Max.) = V<sub>DD</sub> + 1.0V for pulse width ≤ 4 ns acceptable, pulse width measured at 50% of pulse amplitude.
  - \*6. Undershoot limit: V<sub>IL</sub> (Min.) = V<sub>SS</sub> -1.0V for pulse width ≤ 4 ns acceptable, pulse width measured at 50% of pulse amplitude.
- WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

#### **Differential Input Signal Definition**



### ■ CAPACITANCE

 $(T_A = 25^{\circ}C, f = 1 \text{ MHz})$ 

				<b>\</b>	- /
Parameter	Symbol	Min.	Тур.	Max.	Unit
Input Capacitance, Address & Control	CIN1	2.5	_	3.5	pF
Input Capacitance, CLK & CLK	CIN2	2.5	—	3.5	pF
Input Capacitance, DM <sub>0</sub> to DM <sub>3</sub>	Сімз	4.0	—	5.5	pF
I/O Capacitance	Cı/o	4.0	—	5.5	pF

## ■ DC CHARACTERISTICS

## (At recommended operating conditions unless otherwise noted.) Note \*1,\*2,\*3

Damana	4	Ourseland	Condition	Va	Unit	
Parame	eter	Symbol	Condition	Min.	Max.	Unit
Output Minimum Source	DC Current	IOH(DC)	Vddq = 2.3V, Voh = Vddq-0.43V	-15.2	_	mA
Output Minimum Sink D	C Current	IOL(DC)	V <sub>DDQ</sub> = 2.3V, V <sub>OL</sub> = +0.35V	15.2	_	mA
Input Leakage Current (any input)		lu	$0 V \le V_{IN} \le V_{DD}$ ; All other pins not under test = $0 V$	-10	10	μΑ
Output Leakage Current		Ilo	$0 V \le V_{IN} \le V_{DD};$ Data out disabled	-10	10	μA
VREF Current		IREF		-10	10	μΑ
Operating Current (Average Power Supply Current)	MB81P643287-50	- IDD1S	Burst Length = 2 tck = Min., One bank active, Address change up to 3 times dur-	_	460	mA
	MB81P643287-60		$      ing I_{RC} (Min.)  0 V \le V_{IN} \le V_{IL} (Max.),  V_{IH} (Min.) \le V_{IN} \le V_{DD} $		405	
	MB81P643287-50		CKE = $V_{H}$ , tck = Min. All banks idle, NOP commands only,		85	mA
Standby Current	MB81P643287-60	Idd2n	Input signals (except to CMD) are changed one time during 20 ns $0 V \le V_{IN} \le V_{IL}$ (Max.), $V_{IH}$ (Min.) $\le V_{IN} \le V_{DD}$		75	
Power Down Current		Idd2p	$\begin{array}{l} CKE = V_{IL},  t_{CK} = Min.\\ All \ banks \ idle,\\ 0 \ V \leq V_{IN} \leq V_{DD} \end{array}$	_	35	mA
Active Standby Current	MB81P643287-50		CKE = $V_{IH}$ , tck = Min. All banks Active, NOP commands only,	_	260	
(Power Supply Current)	MB81P643287-60	IDD3N	Input signals (except to CMD) are changed one time during 20 ns $0 V \le V_{IN} \le V_{IL}$ (Max.), $V_{IH}$ (Min.) $\le V_{IN} \le V_{DD}$		225 (Con	mA

(Continued)

## MB81P643287-50/-60

Parameter		Symbol	Condition	Va	lue	Unit
Faidi	neter	Symbol	ConditionMin.Burst Length = 4, CAS Latency = 3, All bank active, Gapless data, $t_{CK} = Min.$ , $0 \ V \le V_{IN} \le V_{IL}$ (Max.), $V_{IH}$ (Min.) $\le V_{IN} \le V_{DD}$    Burst Length = 4, CAS Latency = 3, All bank active, Gapless data, $t_{CK} = Min.$ , $0 \ V \le V_{IN} \le V_{IL}$ (Max.), $V_{IH}$ (Min.) $\le V_{IN} \le V_{DD}$ Burst Length = 4, CAS Latency = 3, All bank active, $0 \ V \le V_{IN} \le V_{IL}$ (Max.), $V_{IH}$ (Min.) $\le V_{IN} \le V_{DD}$ Auto-refresh;		Max.	Unit
Burst Read Current	MB81P643287-50		CAS Latency = 3,		535	
(Average Power Supply Current)	MB81P643287-60	IDD4R	tck = Min., 0 V $\leq$ VIN $\leq$ VIL (Max.),	_	460	mA
Burst Write Current	MB81P643287-50CAS Latency = 3,urrentAll bank active,		CAS Latency = 3, All bank active,		595	
(Average Power Supply Current)	MB81P643287-60	IDD4W	tck = Min., 0 V $\leq$ VIN $\leq$ VIL (Max.),		505	mA
Auto-refresh Current	MB81P643287-50		Auto-refresh; tск = Min.,		320	mA
(Average Power Supply Current)	MB81P643287-60	IDD5	$\begin{array}{l} 0 \ V \leq V_{\text{IN}} \leq V_{\text{IL}} \ (\text{Max.}), \\ V_{\text{IH}} \ (\text{Min.}) \leq V_{\text{IN}} \leq V_{\text{DD}} \end{array}$		270	IIIA
Self-refresh Current (Average Power Supp	bly Current)	Idd6	Self-refresh;		5	mA

(Continued)

Notes: \*1. All voltages referenced to Vss.

\*2. DC characteristics are measured after following the POWER-UP INITIALIZATION procedure.

\*3. IDD depends on the output termination or load conditions, clock cycle rate, and number of address and command change within certain period. The specified values are obtained with the output open.

## ■ AC CHARACTERISTICS

### (Recommended operating conditions unless otherwise noted.) Note \*1,\*2,\*3

### AC PARAMETERS (CAS LATENCY DEPENDENT)

Parameter		Symbol		381P643287-50 MB81P643287-60			
Falanielei	Symbol		Min.	Max.	Min.	Max.	Unit
Clock Period	tor	CL = 3	5.0	9.0	6.0	10.5	ns
	tск	CL = 2	7.5	10.5	9.0	10.5	115

Parameter	Notes	Symbol	MB81P6	43287-50	MB81P6	Unit	
Faiameter	Notes	Symbol	Min.	Max.	Min.	Max.	Unit
Input Setup Time (Except for DQS, DM and DQs)	*4	tıs	1.0		1.2		ns
Input Hold Time (Except for DQS, DM and DQs)	*4	tıн	1.0	_	1.2	_	ns
DM and Data Input Setup Time	*5	tos	0.6	—	0.7	—	ns
DM and Data Input Hold Time	*5	tон	0.6	—	0.7	—	ns
DQS First Input Setup Time (Input Preamble Setup Time)	*6	<b>t</b> dspres	0	_	0	_	ns
Last Data Output to CKE High Level Hold Time		<b>t</b> qскен	0	_	0	_	ns
Input Transition Time	*7	t⊤	0.1	0.8	0.1	0.9	ns
Precharge Power Down Exit and Self-refresh Exit Time	*4	<b>t</b> PDEX	3.0	_	3.6	_	ns
Time between Refresh	*8	<b>t</b> REF	—	32	—	32	ms
Time between Auto-refresh Command	*8	<b>t</b> aref	—	8.0	—	8.0	μs
Pause Time after Power-on		<b>t</b> PAUSE	200		200	—	μs

AC PARAMETERS (	FREQUENCY DEPENDANT)	Note *9
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Parameter	Notes	Symbol	Min.	Max.	Unit	
Clock High Time	*4	tсн	0.45 × tск	—	ns	
Clock Low Time	*4	tc∟	0.45 × tск		ns	
DQS Low to High Input Transition Setup Time from CLK	*4, *10	toass	0.75 × tск	1.25 × tск	ns	
DQS Low Input Pulse Width		<b>t</b> DSL	0.4 × tск	—	ns	
DQS High Input Pulse Width		tdsн	0.4 × tск	—	ns	
DQS First Low Input Hold Time (Input Preamble Hold Time)	*4	<b>t</b> dspreh	0.25 × tск	_	ns	
DQS First Low Input Pulse Width (Input Preamble Pulse Width)		<b>t</b> dspre	0.4 × tск	_	ns	
DQS Last Low Input Hold Time (Input Postamble Hold Time)		<b>t</b> dspst	0.4 × tск	_	ns	
DQS Access Time from Clock	*4	<b>t</b> qscк	- 0.1 × tск - 0.2	0.1 × tск + 0.2	ns	
DQS Output Valid Time		<b>t</b> qsv	0.3 × tск	—	ns	
DQS Output in Low-Z (Output Preamble Setup Time)	*4, *11	tqs∟z	- 0.1 × tск - 0.2	_	ns	
DQS First Low Output Hold Time (Output Preamble Hold Time)	*4	<b>t</b> qspre	0.9 × tск - 0.2	1.1 × tск + 0.2	ns	
DQS Last Low Output Hold Time (Output Postamble Hold Time)	*4, *12	<b>t</b> qspst	0.4 × tск - 0.2	0.6 × tск + 0.2	ns	
DQS Last Low Output in High-Z from CLK or CLK	*12	tqsнz		0.1 × tск + 0.2	ns	
DQ Access Time from CLK & CLK	*4	tacc	- 0.1 × tск - 0.2	0.1 × tск + 0.2	ns	
DQ Access Time from DQS	*5	<b>t</b> asa	- 0.1 × tск	0.1 × tск	ns	
DQ Output Data Valid Time from DQS		t <sub>DV</sub>	0.3 × tск	—	ns	
DQ Output in Low-Z	*4, *11	t∟z	- 0.1 × tск - 0.2	—	ns	
DQ Output in High-Z	*4, *12	tнz	- 0.1 × tск - 0.2	0.1 × tск + 0.2	ns	
DQ & DM Input Pulse Width		<b>t</b> DIPW	0.4 × tск	—	ns	
DQS Falling Edge to Clock Hold Time		tdscн	0.2 × tск (1.5 ns Min.)	_	ns	
DQS Falling Edge to Clock Setup Time		toscs	0.2 × tск (1.5 ns Min.)	_	ns	

#### EXAMPLE OF FREQUENCY DEPENDANT AC PARAMETERS (@ Minimum tck)

		t <sub>ск</sub> = 5ns			6ns	1	7.5ns			tск = 10.5ns		
Parameter	Symbol	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
Clock High Time	tсн	2.3	—	2.7	—	3.4		4.1		4.8		ns
Clock Low Time	tc∟	2.3	—	2.7	—	3.4		4.1		4.8		ns
DQS Low to High Input Transition Setup Time from CLK	tdqss	3.8	6.3	4.5	7.5	5.7	9.4	6.8	11.3	7.9	13.2	ns
DQS Low Input Pulse Width	<b>t</b> DSL	2.0	—	2.4	—	3.0	—	3.6	—	4.2	—	ns
DQS High Input Pulse Width	tdsн	2.0	—	2.4	_	3.0	—	3.6		4.2		ns
DQS First Low Input Hold Time (Input Preamble Hold Time)	<b>t</b> dspreh	1.3	_	1.5	_	1.9	_	2.3	_	2.7	_	ns
DQS First Low Input Pulse Width (Input Preamble Pulse Width)	<b>t</b> dspre	2.0	_	2.4	_	3.0	_	3.6	_	4.2	_	ns
DQS Last Low Input Hold Time (Postamble Hold Time)	<b>t</b> dspst	2.0	_	2.4	_	3.0	_	3.6	_	4.2	_	ns
DQS Access Time from Clock	<b>t</b> qsck	-0.7	0.7	-0.8	0.8	-1.0	1.0	-1.1	1.1	-1.3	1.3	ns
DQS Output Valid Time	<b>t</b> qsv	1.5	—	1.8	—	2.3	—	2.7	—	3.2	—	ns
DQS Output in Low-Z (Output Preamble)	<b>t</b> qslz	-0.7	_	-0.8	_	-1.0	_	-1.1	_	-1.3	_	ns
DQS First Low Output Hold Time (Output Preamble)	<b>t</b> qspre	4.3	5.7	5.2	6.8	6.6	8.5	7.9	10.1	9.3	11.8	ns
DQS Last Low Output Hold Time (Output Postamble)	<b>t</b> qspst	1.8	3.2	2.2	3.8	2.8	4.7	3.4	5.6	4.0	6.5	ns
DQS Last Low Output in High-Z from CLK or CLK	tqsнz	_	0.7	-	0.8	_	1.0	_	1.1	_	1.3	ns
DQ Output Access Time from CLK & CLK	tacc	-0.7	0.7	-0.8	0.8	-1.0	1.0	-1.1	1.1	-1.3	1.3	ns
DQ Output Access Time from DQS	tasa	-0.5	0.5	-0.6	0.6	-0.8	0.8	-0.9	0.9	-1.1	1.1	ns
DQ Output Data Valid Time from DQS	tov	1.5	_	1.8	_	2.3	_	2.7	_	3.2		ns
DQ Output in Low-Z	t∟z	-0.7	—	-0.8	—	-1.0	—	-1.1		-1.3	_	ns
DQ Output in High-Z	tнz	-0.7	0.7	-0.8	0.8	-1.0	1.0	-1.1	1.1	-1.3	1.3	ns
DQ & DM Input Pulse Width	<b>t</b> DIPW	2.0	—	2.4		3.0	—	3.6	—	4.2		ns
DQS Falling Edge to Clock Hold Time	tdscн	1.5	_	1.5	_	1.5	_	1.8	_	2.1	_	ns
DQS Falling Edge to Clock Setup Time	toscs	1.5	—	1.5	_	1.5	_	1.8	—	2.1	_	ns

### LATENCY

(The latency values on these parameters are fixed regardless of clock period.)

Parameter	Notes	Symbol	MB81P64	43287-50	MB81P64	Unit	
Farameter	Notes	Symbol	Min.	Max.	Min.	Max.	Onit
RAS Cycle Time *13	CL = 3	IRC	6	_	6		tск
RAS Cycle Tille 15	CL = 2	IRC	5	_	5	_	tск
RAS Active Time	CL = 3	RAS	4	11000	4	11000	tск
RAS Active Time	CL = 2	IRAS	3	7333	3	7333	tск
RAS Precharge Time		Irp	2	—	2	_	tск
RAS to CAS Delay Time	CL = 3	IRCD	3	_	3	_	tск
RAS to CAS Delay Time	CL = 2	IRCD	2	_	2	_	tск
RAS to RAS Bank Active Delay	Time	Irrd	1	_	1	_	tск
Procharge All Bank to Active	CL = 3	RPA	4	—	4	_	tск
Precharge All Bank to Active	CL = 2	IRPA	3	_	3	_	tск
Read Command to Write	CL = 3	RWD	BL/2+3	_	BL/2+3	_	tск
Command Delay	CL = 2	IRWD	BL/2+2	_	BL/2+2	_	tск
Last Input Data to Read Command *14 Delay		Iwrd	2.5	_	2.5	_	tск
Last Input Data to Precharge Command Lead Time *14		Idpl	2.5	_	2.5	—	tск
Write with Auto Precharge Com Active command Delay	mand to *14	Iwal	BL/2+3+Irp	_	BL/2+3+IRP	_	tск
Mode Register Access to Next 0 Input Delay	Command	Imrd	2	_	2	_	tск
CAS to CAS Delay		Ісср	1	—	1	_	tск
CAS Bank Delay		Ісвр	1		1		tск
Precharge Power Down Exit to Command Input Delay	Next	IPDEXP	2	_	2	_	tск
Minimum Stable Clock Input After refresh Exit Before READ Comr		Iscd	400	_	400	_	tск
Minimum Stable Clock Input After Self- refresh Exit Before non-READ Command Input		Ixsnr	12	_	12	_	tск
Minimum Stable Clock Input for	tск ≤ <b>7.5ns</b>		400	—	400	_	tск
DLL Lock-on in Power-up Initialization sequence. *16	tcκ ≤ 10.5ns	IPCD	630	_	630		tск
Auto-refresh Cycle Time		IRFC	12	—	12	—	tск

#### LATENCY - FIXED VALUES

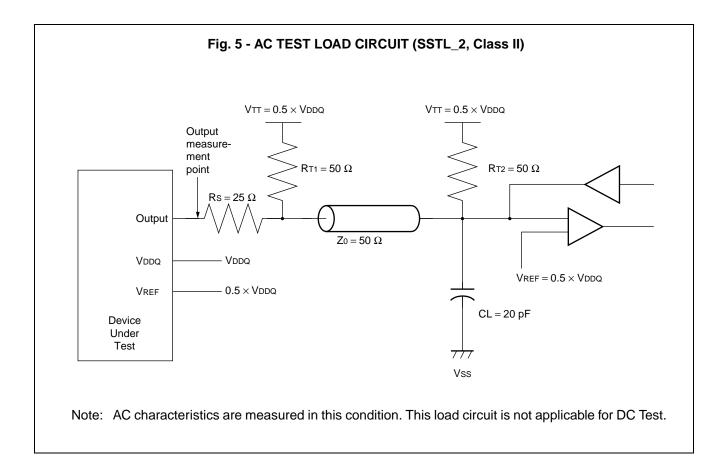
#### (The latency values on these parameters are fixed regardless of clock period.)

Parameter	Notes	Symbol	MB81P643287-50	MB81P643287-60	Unit
BST Command to Output in High-Z	CL = 3	la ou	3	3	tск
BST Command to Output in Figh-2	CL = 2	IBSH	2	2	tск
BST Command to New Command Input *17	CL = 3	Inaula	3	3	tск
	CL = 2	IBSNC	2	2	tск
DM to Input Data Delay		Idqd	0	0	tск
Prochargo to Output in High Z	CL = 3	Incu	3	3	tск
Precharge to Output in High-Z	CL = 2	ROH	2	2	tск
CKE Low to Command/Address Input Inactiv	ve	Іске	1	1	tск

- Notes: \*1. AC characteristics are measured after following the POWER-UP INITIALIZATION procedure and stable clock input with constant clock period and with 50% duty cycle.
  - \*2. Access Times assume input slew rate of 1ns/volt between VREF+0.35V to VREF-0.35V, where VREF is VDDQ/2, with SSTL\_2 output load conditions. Refer to AC TEST LOAD CIRCUIT.
  - \*3. V<sub>REF</sub> = 1.25V is a typical reference level for measuring timing of input signals. Transition times are measured between V<sub>IH</sub>(Min.) and V<sub>IL</sub>(Max.) unless otherwise noted. Refer to AC TEST CONDITIONS.
  - \*4. This parameter is measured from the cross point of CLK and CLK input.
  - \*5. This parameter is measured from signal transition point of DQS<sub>0</sub> to DQS<sub>3</sub> input crossing VREF level.
  - \*6. The specific requirement is that DQS be valid (HIGH or LOW) on or before this CLK edge. The case shown (DQS going from High-Z to logic LOW) applies when no writes were previously in progress on the bus. If a previous write was in progress, DQS could be HIGH at this time, depending on tbss.
  - \*7. tr is defined as the transition time between VIH (AC)(Min.) and VIL (AC)(Max.).
  - \*8. Total of 4096 REF command must be issued within tREF (Max.). tAREF is a reference value for distributed refresh and specifies the time between one REF command to next REF command except for a condition where CKE = Low during Self-refresh mode.
  - \*9. This parameter is scalable by actual clock period (tcκ) and affected by an abrupt change of duty cycle, jitters on clock input, T<sub>A</sub> and level of V<sub>DD</sub> and V<sub>DDQ</sub>. The internal DLL circuit can adjust delay time against the change of following condition :
    - T<sub>A</sub> ≤ 0.1 °C / 20 ns,
    - $V_{DD} \le 1 \text{ mV} / 10 \text{ ns},$
    - $V_{DDQ} \leq 1 \text{ mV} / 10 \text{ ns},$

if change rate is bigger than these values, frequency dependent AC parameters affected by DLL jitters.

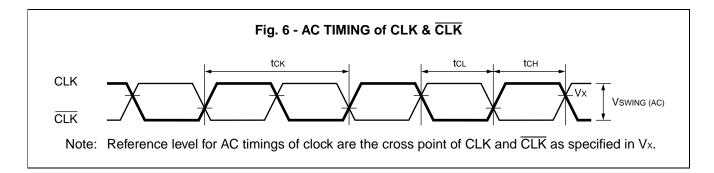
- \*10. More than 2 signal edge of DQS<sub>0</sub> to DQS<sub>3</sub> should not be input within 1 clock (tck) cycle.
- \*11. Low-Z (Low Impedance State) is specified and measured at V $\pi$  ± 200mV.
- \*12. taspst, tashz and the are specified where output buffer is no longer driven.
- \*13. Actual clock count of IRC will be sum of clock count of IRAS and IRP.
- \*14. Assume  $t_{DQSS} = 1 \times t_{CK}$ . If actual  $t_{DQSS}$  is within specified minimum and maximum range, those parameters can be assumed  $t_{DQSS} = 1 \times t_{CK}$ .
- \*15. Applicable also if device operating conditions such as supply voltages, case temperature, and/or clock frequency (tck difference must be 0.2 ns or less) is changed during any operation.
- \*16. Clock period must satisfy specified tck and it must be stable.
- \*17. Assume BST is effective to read operation (issued prior to the end of burst read).

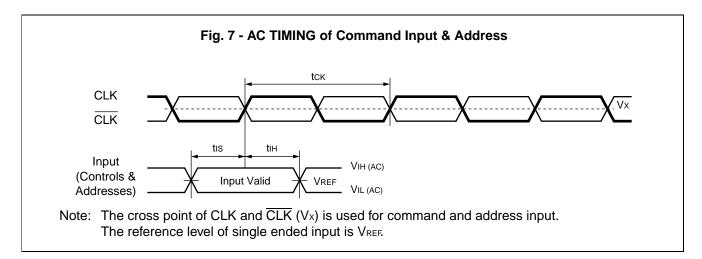


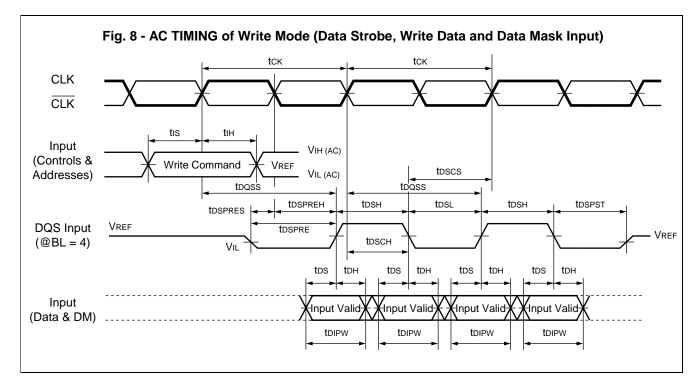
#### AC TEST CONDITIONS

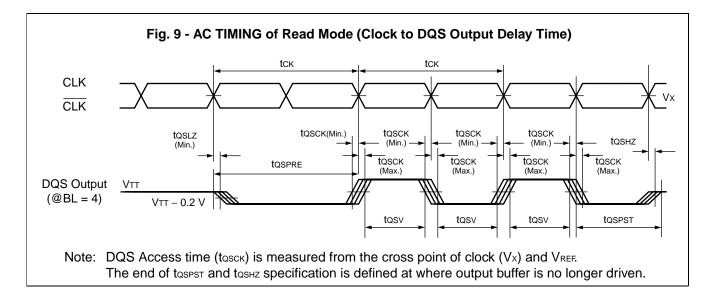
Parameters	Symbol	Value	Unit
Single-end Input			
Input High Level	Vін	Vref + 0.35	V
Input Low Level	VIL	$V_{\text{REF}} - 0.35$	V
Input Reference Level	Vref	Vddq / 2	V
Input Slew Rate	SLEW	SLEW 1.0	
Differential Input (CLK and CLK)			L.
Input Reference Level	Vr	Vx (AC)*	V
Input Level	Vswing	0.7	V
Input Slew Rate	SLEW	1.0	V/ns

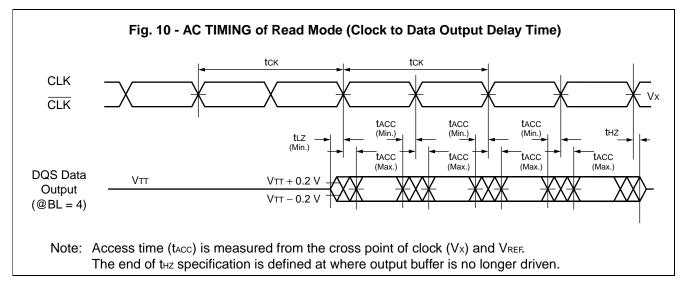
\* : Vx means the actual cross point between CLK and  $\overline{\text{CLK}}$  input.

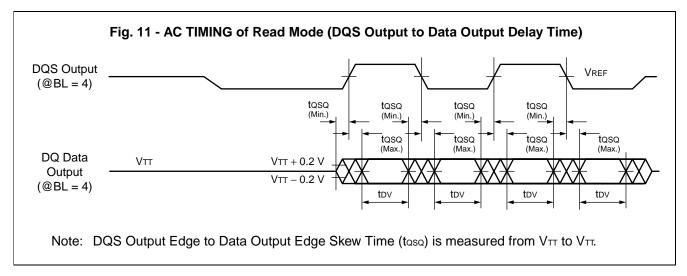


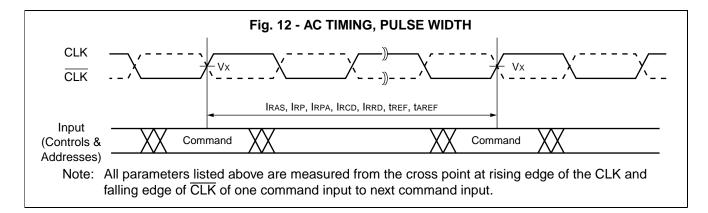


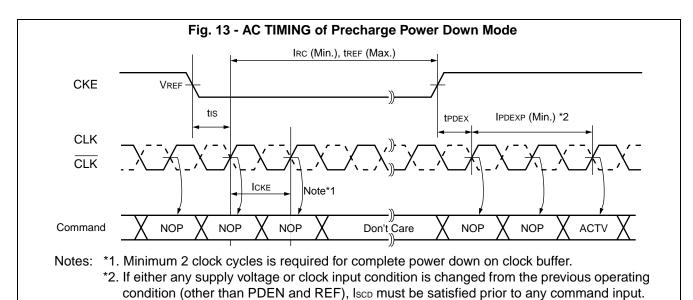


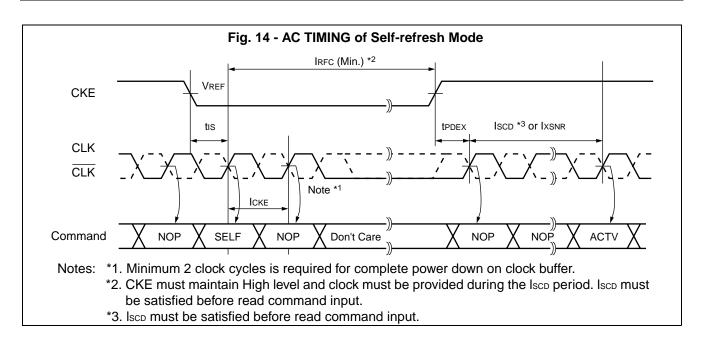




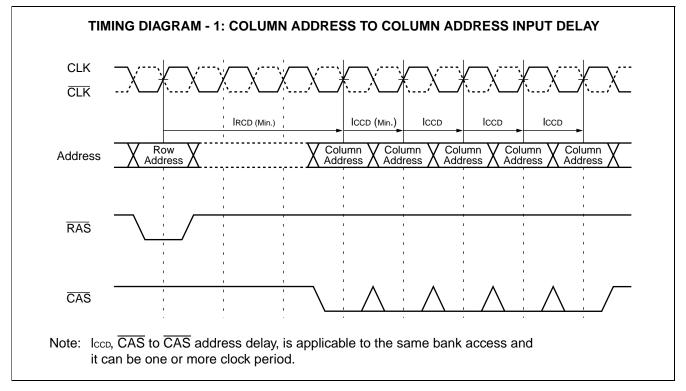


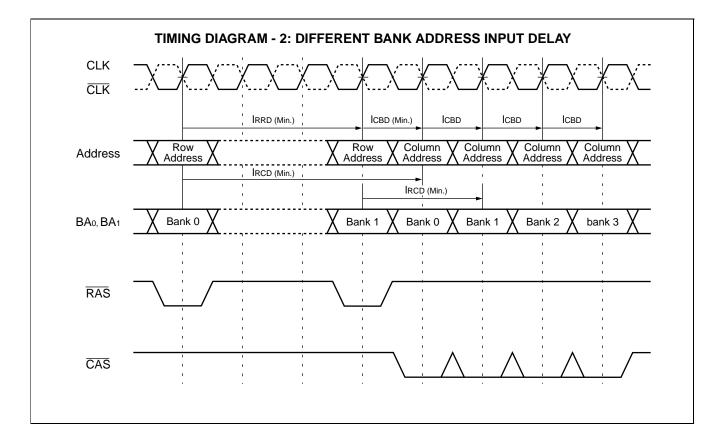


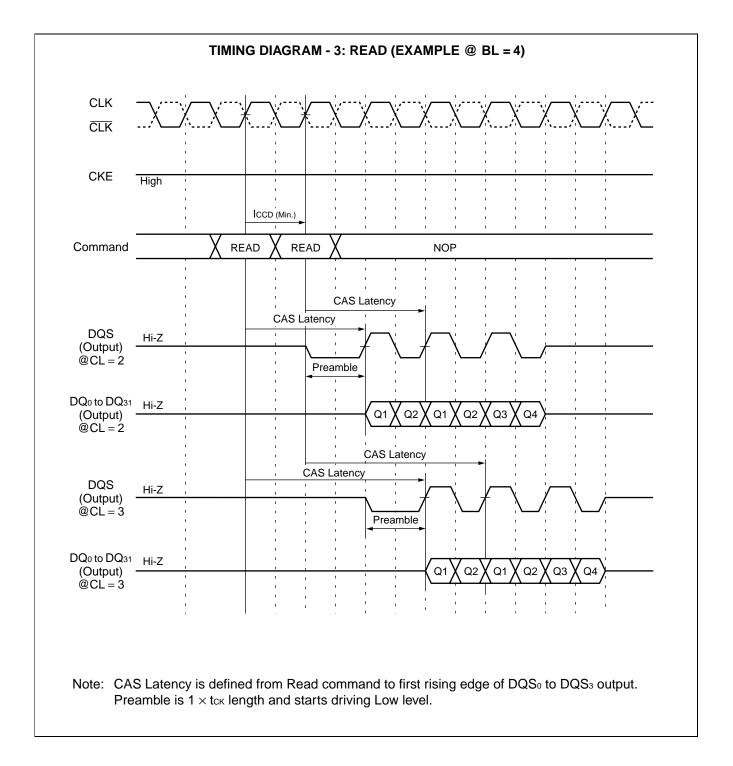


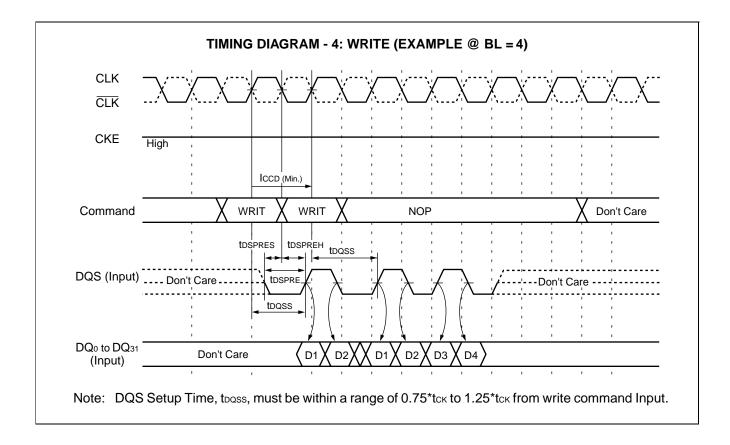


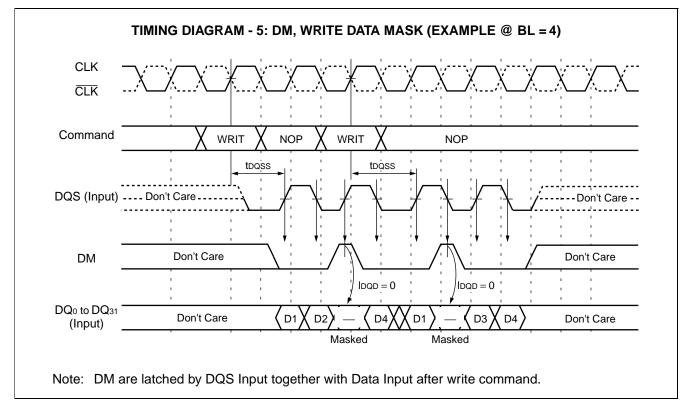
### TIMING DIAGRAMS

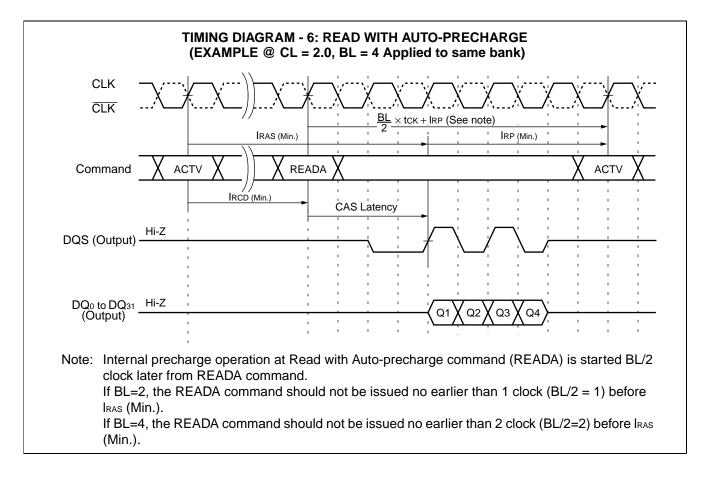


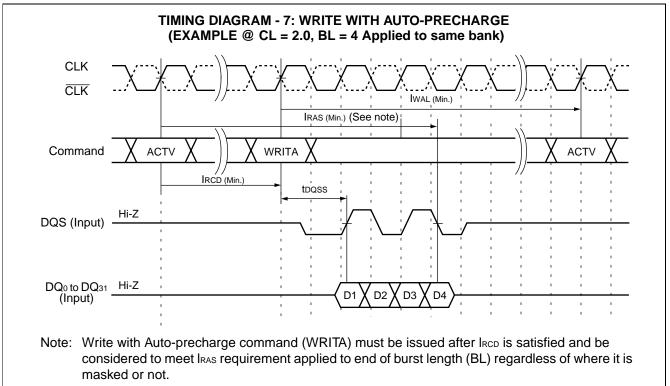


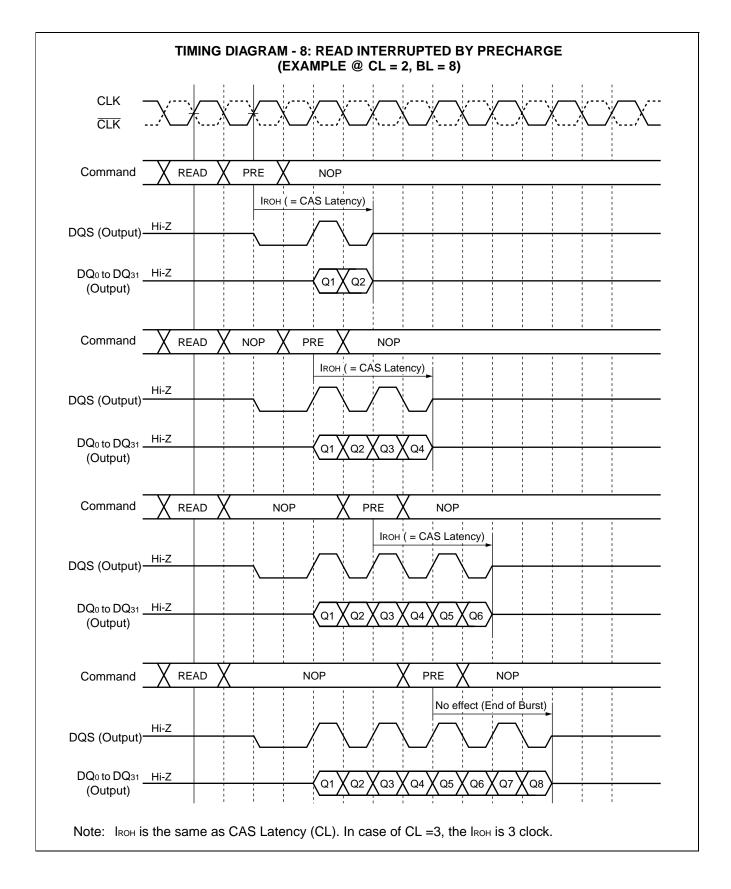


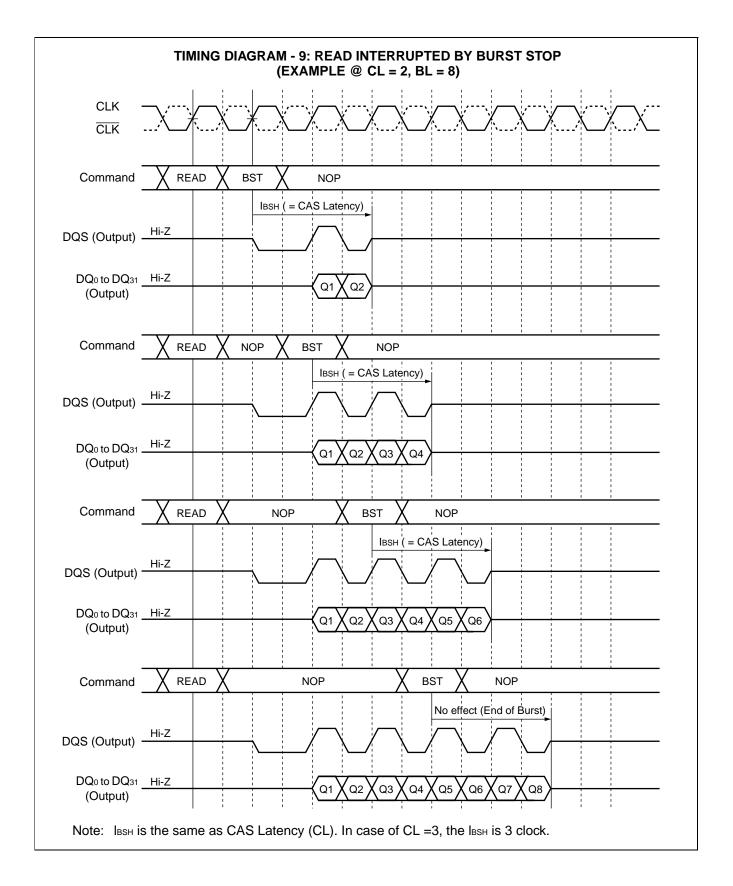


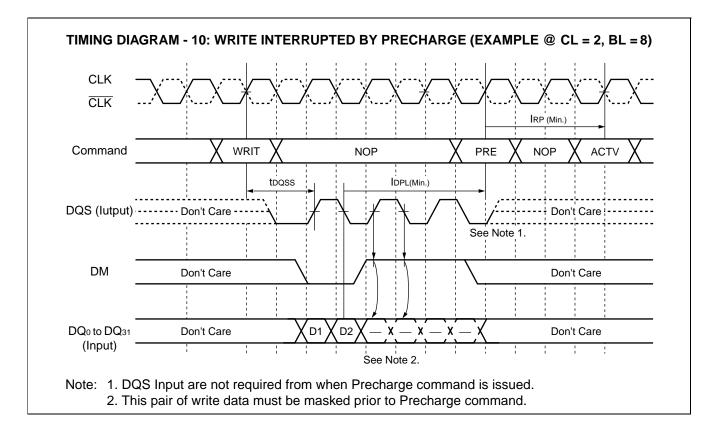


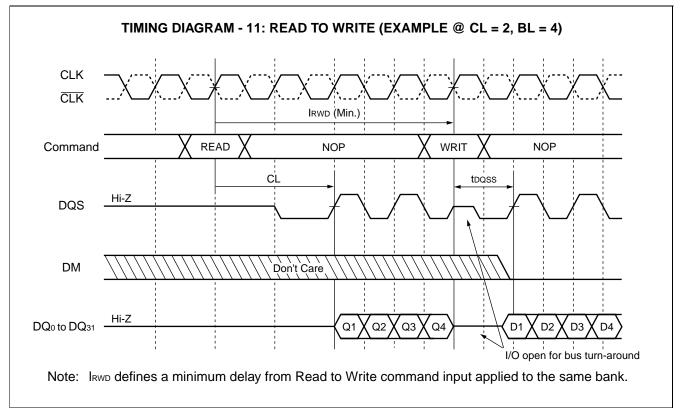


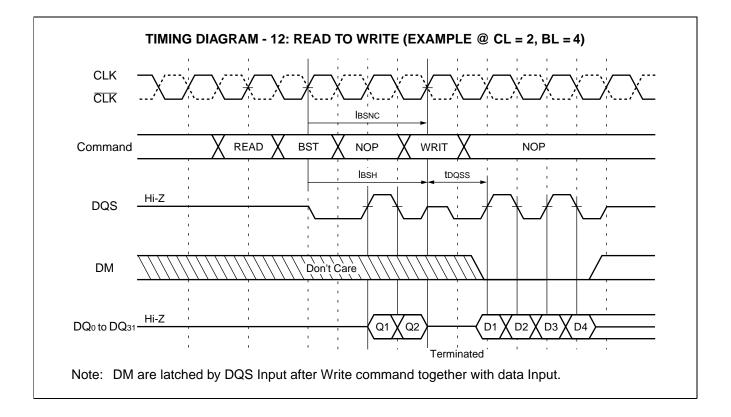


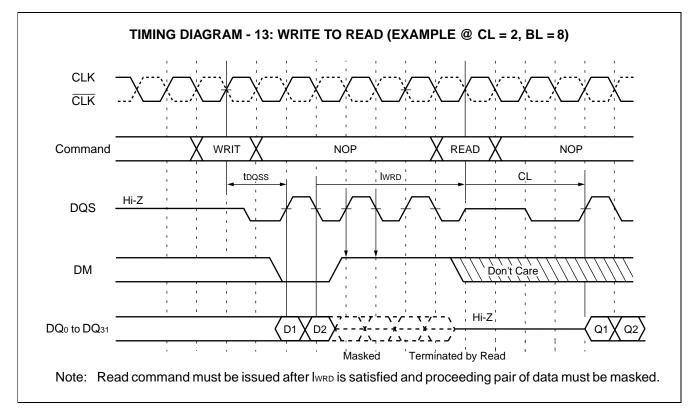


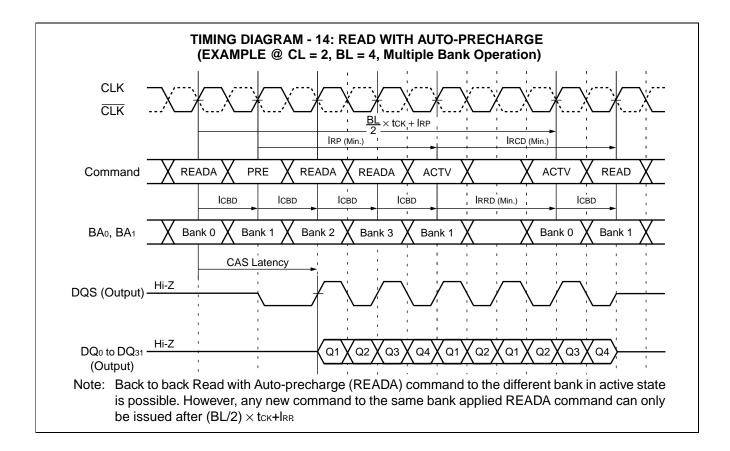


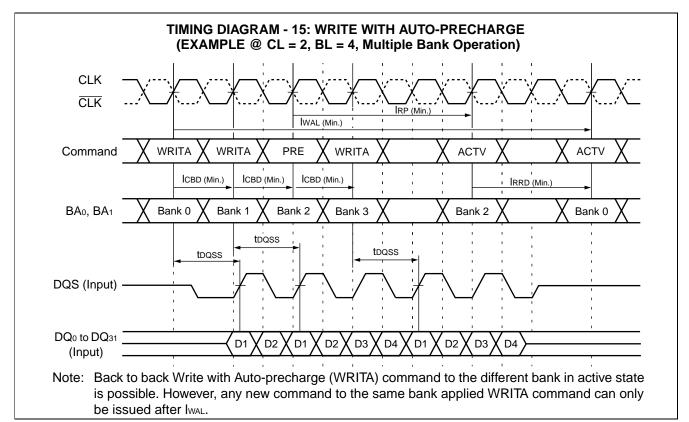


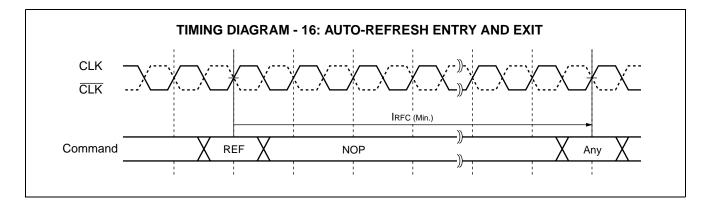


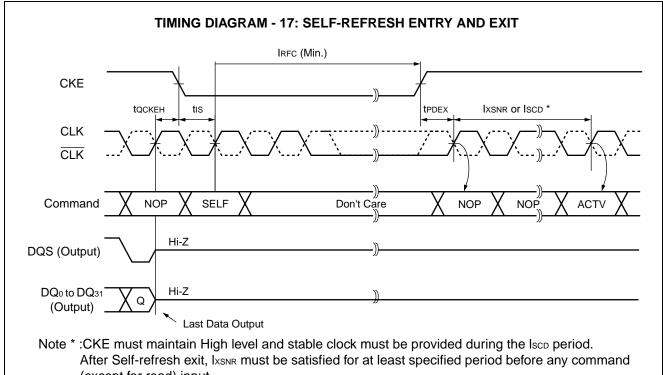


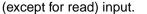


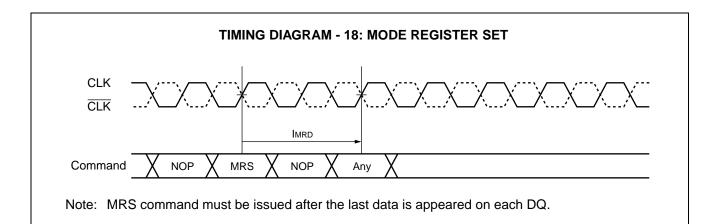








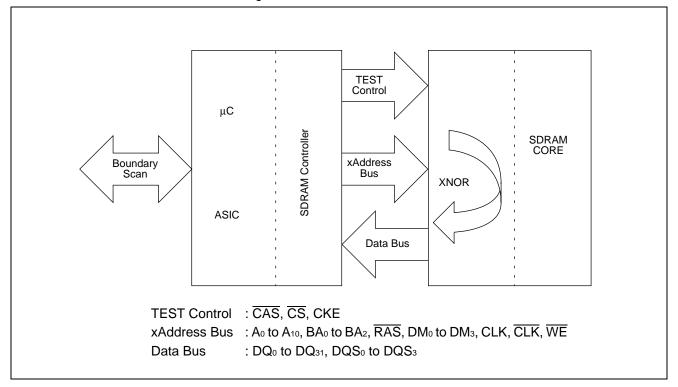




### SCITT TEST MODE

### ABOUT SCITT

SCITT (Static Component Interconnection Test Technology) is an XNOR circuit based test technology that is used for testing interconnection between SDRAM and SDRAM controller on the printed circuit boards. SCITT provides inexpensive board level test mode in combination with boundary-scan. The basic idea is simple, consider all output of SDRAM as output of XNOR circuit and each output pin has a unique mapping on the input of SDRAM. The ideal schematic block diagram is as shown below.



It is static and provides easy test pattern that result in a high diagnostic resolution for detecting all open/short faults.

### SCITT TEST SEQUENCE

The followings are the SCITT test sequence. SCITT Test can be executed after power-on and prior to Precharge command in "■ FUNCTION DESCRIPTION POWER-UP INITIALIZATION". Once Precharge command is issued to SDRAM, it never get back to SCITT Test Mode during regular operation unless reset power supply for the purpose of a fail-safe way in get in and out of test mode.

- 1. Maintain all input signals (except CLK, CLK) to be Low state (or at least CKE to be Low) and maintain CLK and CLK to be complementary state.
- 2. Apply  $V_{DD}$  voltage to all  $V_{DD}$  pins before or at the same time as  $V_{DDQ}$  pins.
- 3. Apply  $V_{DD}$  voltage to all  $V_{DDQ}$  pins before or at the same time as  $V_{REF}$  and  $V_{TT}$ .
- 4. Apply VREF and VTT (VTT is applied to the system).
- 5. Maintain stable power for a minimum of 100µs.
- 6. Enter SCITT test mode.
- 7. Execute SCITT test.
- 8. Exit from SCITT mode.

It is required to follow Power On Sequence to execute read or write operation.

- 9. Start clock after all power supplies reached in a specified operating range and maintain stable condition for a minimum of 200μs.
- 10. After the minimum of 200μs stable power and clock, apply NOP condition and take CKE to be High state.
- 11. Issue Precharge All Banks (PALL) command or Precharge Single Bank (PRE) command to every banks.
- 12. Issue EMRS to enable DLL, DE = Low.
- Issue Mode Register Set command (MRS) to reset DLL, DR = High. An additional clock input for IPCD\*1
  period is required to lock the DLL.
- 14. Apply minimum of two Auto-refresh command (REF).\*2
- 15. Program the mode register by Mode Register Set command (MRS) with DR = Low.\*2

The 6,7,8 steps define the SCITT mode available. It is possible to skip these steps if necessary (Refer to "■ FUNC-TION DESCRIPTION POWER-UP INITIALIZATION").

- Notes: \*1. The IPCD depends on operating clock period. The IPCD is counted from "DLL Reset" at step-13 to any command input at step-15.
  - \*2. The Mode Register Set command (MRS) can be issued before two Auto-refresh cycle.

### COMMAND TRUTH TABLE Note \*1

	Co	ontrol		Input			Output				
	CAS	CS	CKE	WE	RAS	A <sub>0</sub> to A <sub>10</sub> , BA <sub>0</sub> to BA <sub>2</sub>	DM₀ to DM₃	CLK	CLK	DQ0 to DQ31	DQS₀ to DQS₃
SCITT mode entry	H_\  *2	1	1	х	х	х	х	Н	L	х	х
	· ·−→∟	L	-	Λ	~	Λ	Χ	L	Н		
SCITT mode exit	L→H *3	H *5	L *5	Х	Х	Х	Х	Х	Х	Х	Х
SCITT mode output enable *4	L	L	Н	V	V	V	V	V	V	V	V

Notes: \*1. L = Logic Low, H = Logic High, V = Valid, X = either L or H

\*2. The SCITT mode entry command assumes the first  $\overline{CAS}$  falling edge with  $\overline{CS} = CKE = L$  and  $CLK, \overline{CLK}$  signals are complementary after power on.

\*3. The SCITT mode exit command assumes the first CAS rising edge after the test mode entry.

\*4. Refer the test code table.

\*5.  $\overline{CS}$  = H or CKE = L is necessary to disable outputs in SCITT mode exit.

### TEST CODE TABLE

 $DQ_0$  to  $DQ_{31}$  and  $DQS_0$  to  $DQS_3$  output data is static and is determined by following logic during the SCITT mode operation.

$DQ_0 = \overline{RAS} \text{ xnor } A_0$	$DQ_{12} = \overline{RAS} \operatorname{xnor} BA_0$	$DQ_{24} = A_0 \operatorname{xnor} A_4$
$DQ_1 = \overline{RAS} \text{ xnor } A_1$	$DQ_{13} = \overline{RAS} \text{ xnor } BA_2$	$DQ_{25} = A_0 \operatorname{xnor} A_5$
$DQ_2 = \overline{RAS} \operatorname{xnor} A_2$	$DQ_{14} = \overline{RAS} \operatorname{xnor} DM_0$	$DQ_{26} = A_0 \operatorname{xnor} A_6$
$DQ_3 = \overline{RAS} \text{ xnor } A_3$	$DQ_{15} = \overline{RAS} \text{ xnor } DM_1$	$DQ_{27} = A_0 \operatorname{xnor} A_7$
$DQ_4 = \overline{RAS} \text{ xnor } A_4$	$DQ_{16} = \overline{RAS} \text{ xnor } DM_2$	$DQ_{28} = A_0 \operatorname{xnor} A_8$
DQ₅ = RAS xnor A₅	$DQ_{17} = \overline{RAS} \text{ xnor } DM_3$	$DQ_{29} = A_0 \operatorname{xnor} A_9$
$DQ_6 = \overline{RAS} \text{ xnor } A_6$	$DQ_{18} = \overline{RAS} \text{ xnor CLK}$	$DQ_{30} = A_0 \text{ xnor } A_{10}$
$DQ_7 = \overline{RAS} \text{ xnor } A_7$	$DQ_{19} = \overline{RAS} \text{ xnor } \overline{CLK}$	$DQ_{31} = A_0 \operatorname{xnor} BA_0$
$DQ_8 = \overline{RAS} \text{ xnor } A_8$	$DQ_{20} = \overline{RAS} \text{ xnor } \overline{WE}$	$DQS_0 = A_0 \text{ xnor } BA_1$
$DQ_9 = \overline{RAS} \text{ xnor } A_9$	$DQ_{21} = A_0 \operatorname{xnor} A_1$	$DQS_1 = A_0 \text{ xnor } BA_2$
$DQ_{10} = \overline{RAS} \operatorname{xnor} A_{10}$	$DQ_{22} = A_0 \operatorname{xnor} A_2$	$DQS_2 = A_0 \text{ xnor } DM_0$
$DQ_{11} = \overline{RAS} \text{ xnor } BA_1$	$DQ_{23} = A_0 \operatorname{xnor} A_3$	$DQS_3 = A_0 \text{ xnor } DM_1$

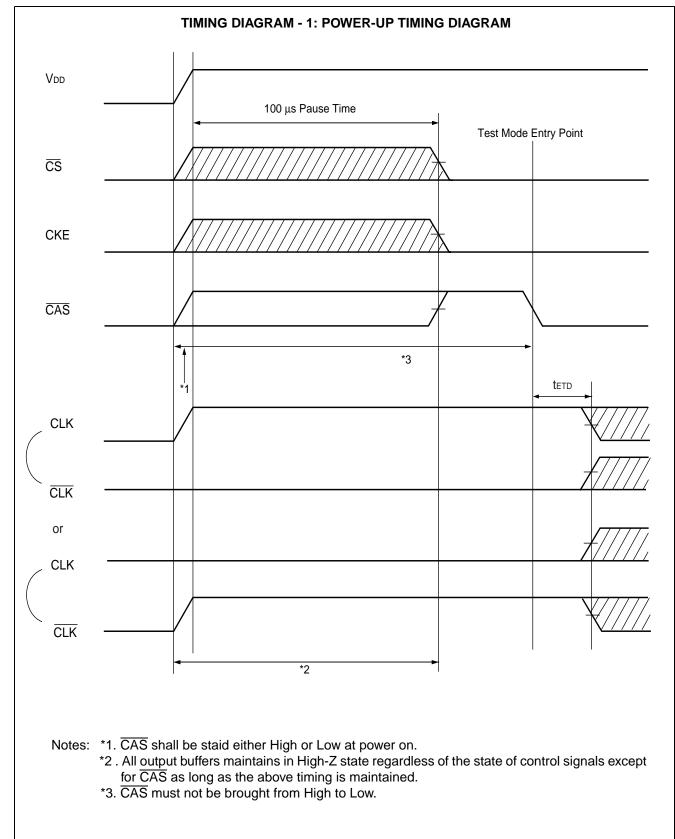
• EXAMPLE OF TEST CODE TABLE

Input bus	Output bus
VERVERSE A A A A A A A A A A A A A A A A A A A	
$ \begin{array}{c} 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 $	H         H

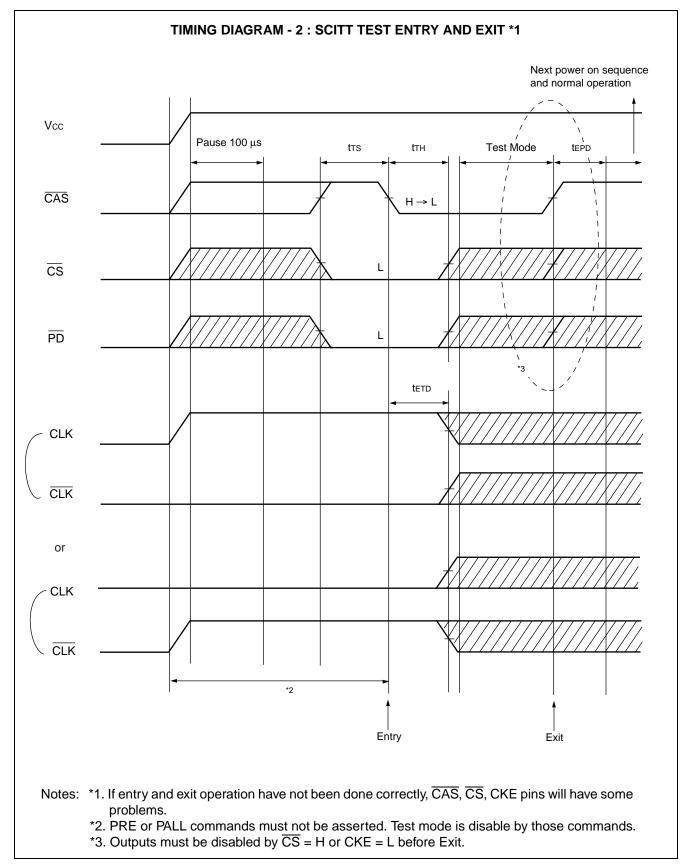
0 =input Low, 1 =input High, L =output Low, H =output High

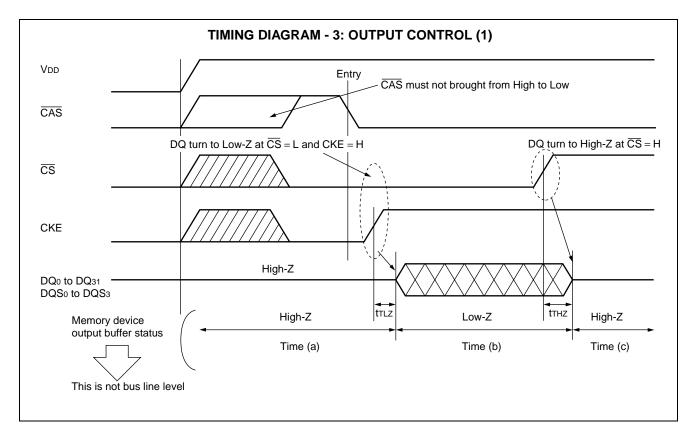
### AC SPECIFICATION

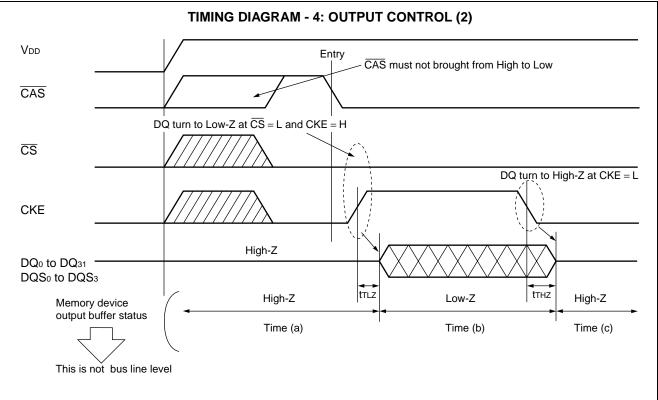
Parameter	Description	Min.	Max.	Units
t⊤s	Test mode entry set up time	10	—	ns
tтн	Test mode entry hold time	10	—	ns
<b>t</b> epd	Test mode exit to power on sequence delay time	10	—	ns
t⊤∟z	CS, CKE to output in Low-Z time	0	—	ns
tтнz	CS, CKE to output in High-Z time	0	20	ns
tтса	Test mode access time from control signals (clock enable & chip select)	_	40	ns
<b>t</b> tia	tTIA Test mode Input access time		20	ns
tтон	tтон Test mode Output Hold time		—	ns
<b>t</b> etd	tetd Test mode entry to test delay time		—	ns
tтıн	Test mode input hold time	30		ns

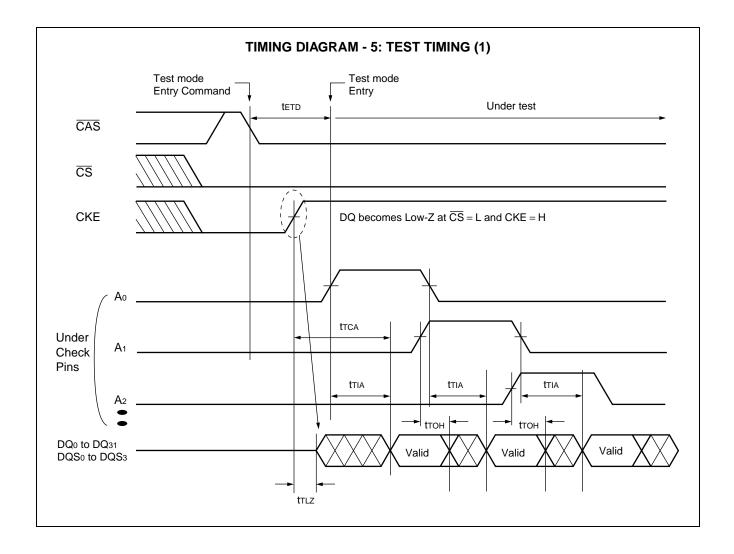


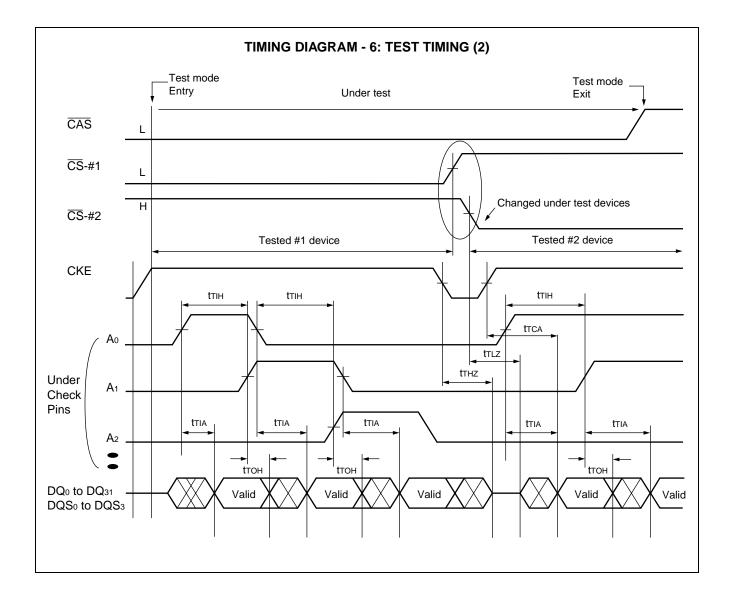
#### **TIMING DIAGRAMS**

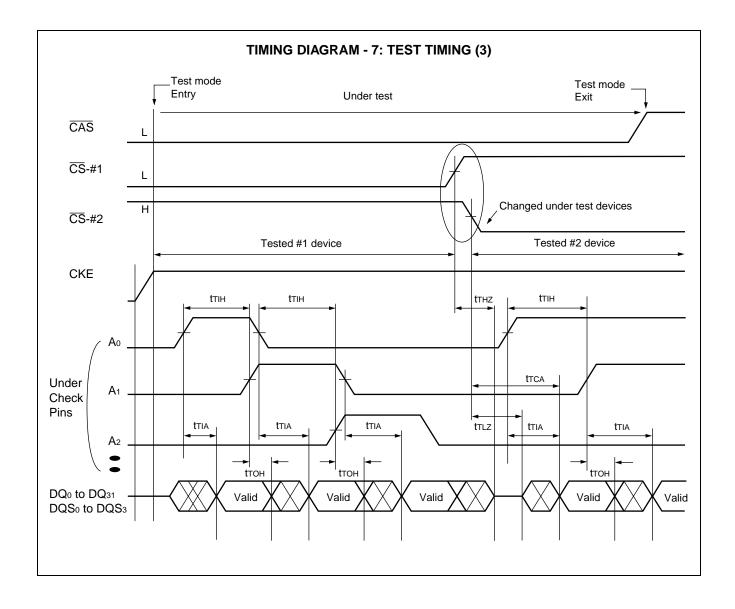








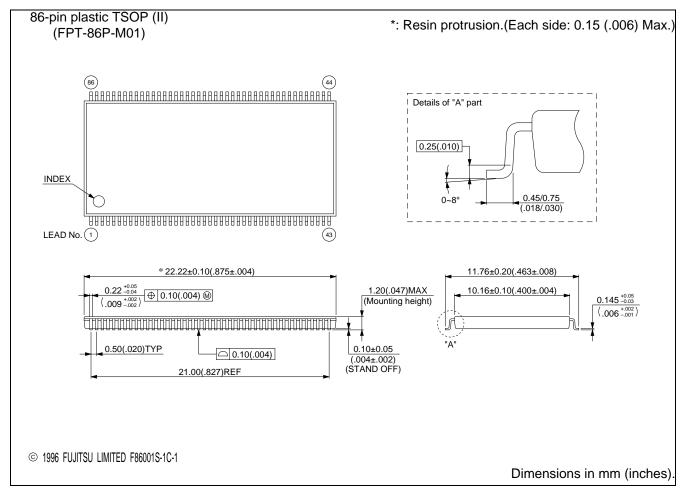




### ■ ORDERING INFORMATION

Part number	Package	Remarks
MB81P643287-50FN	86-pin plastic TSOP(II)	
MB81P643287-60FN	(FPT-86P-M01)	—

### ■ PACKAGE DIMENSIONS



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